

The Field-Effect Transistor (FET)

MOSFET

- ❑ The **metal-oxide-semiconductor field-effect transistor** (MOSFET) becomes a practical reality in the 1970s.
- ❑ The MOSFET, compared to BJTs, can be made very small, that is, it occupies a very small area in IC chip.
- ❑ In the MOSFET, the current is controlled by an electric field applied perpendicular to both the semiconductor surface and to the direction of current.
- ❑ The phenomenon applying an electric field perpendicular to the surface is called the **field effect**.
- ❑ Basic MOS capacitor structure

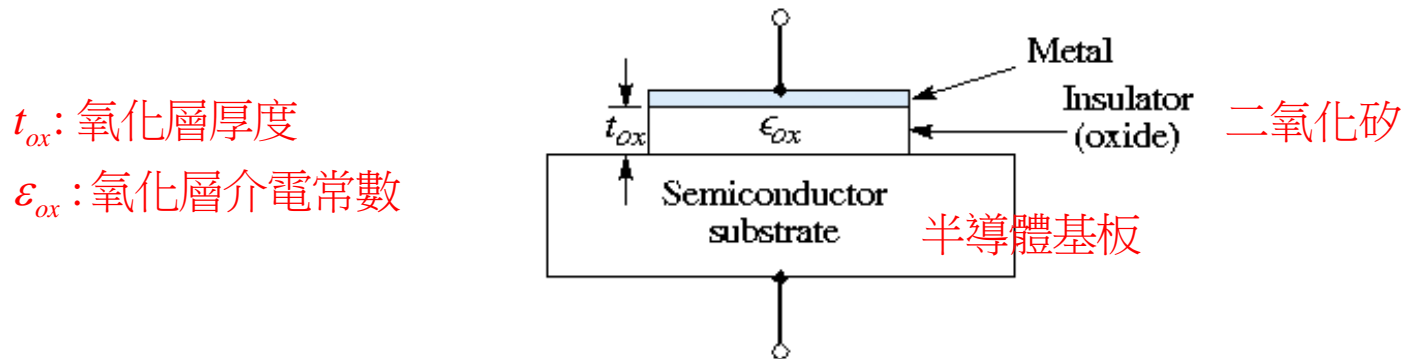


Figure 5.1 The basic MOS capacitor structure

The Physics of the MOS Capacitor

P型基板

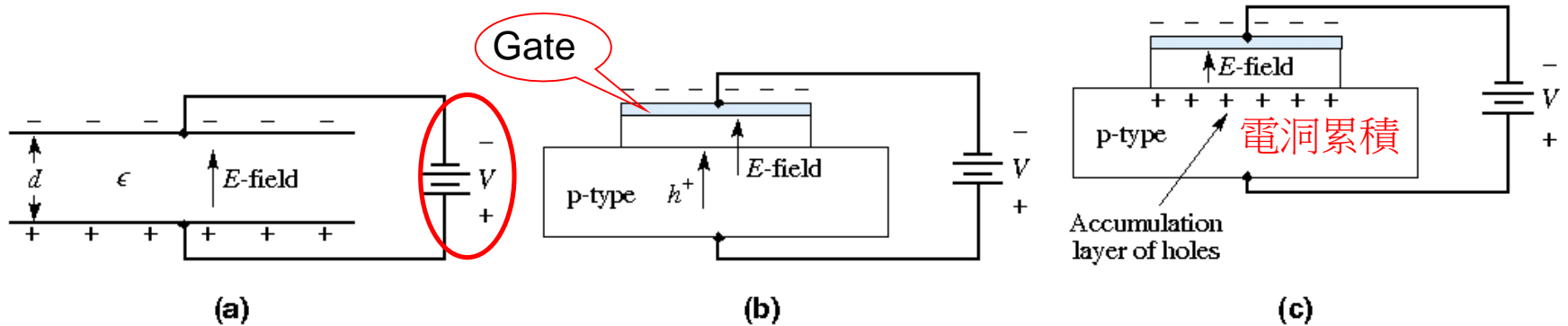


Figure 5.2 (a) A parallel-plate capacitor, showing the electric field and conductor charges, (b) a corresponding MOS capacitor with a negative gate bias, showing the electric field and charge flow, and (c) the MOS capacitor with an accumulation layer of holes

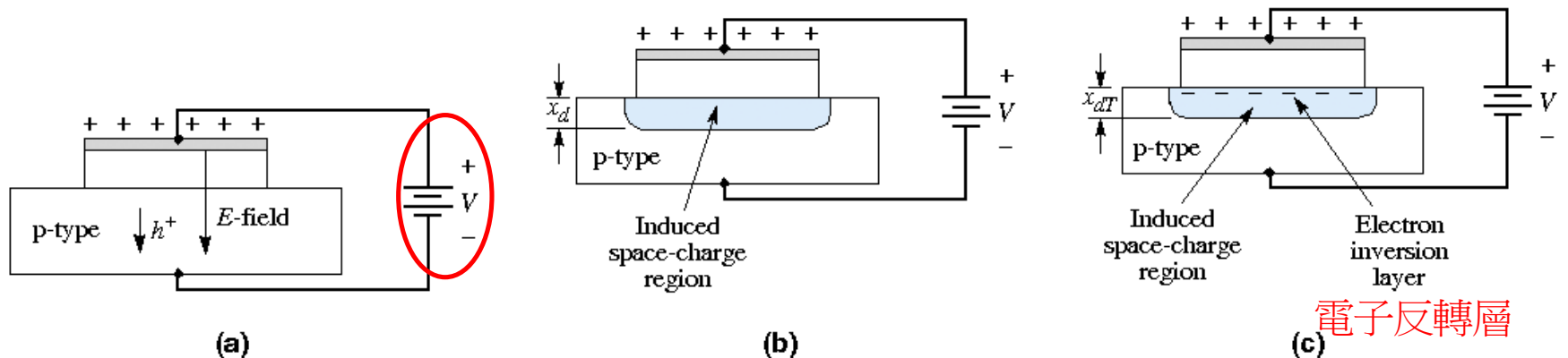


Figure 5.3 The MOS capacitor with p-type substrate: (a) effect of positive gate bias, showing the electric field and charge flow, (b) the MOS capacitor with an induced space-charge region due to a moderate gate bias, and (c) the MOS capacitor with an induced space-charge region and electron inversion layer due to a larger gate bias

The Physics of the MOS Capacitor for N-type Semiconductor Substrate

N型基板

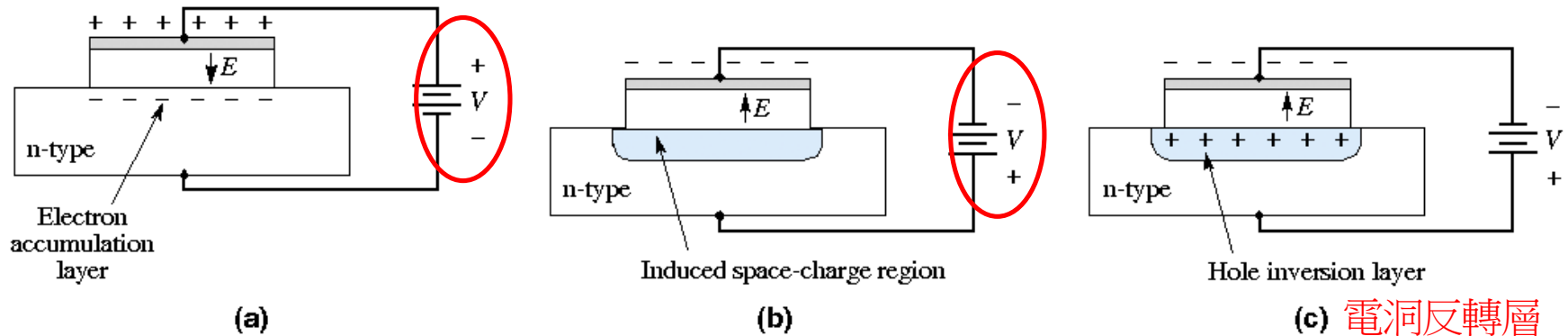


Figure 5.4 The MOS capacitor with n-type substrate for: (a) a positive gate bias, (b) a moderate negative bias, and (c) a larger negative bias

- ❑ Enhancement mode: a voltage must be applied to the gate to create an inversion layer.
 - ✓ P-type: a positive gate voltage must be applied to create the electron inversion layer
 - ✓ N-type: a negative gate voltage must be applied to create the hole inversion layer

NMOS

Transistor Structure

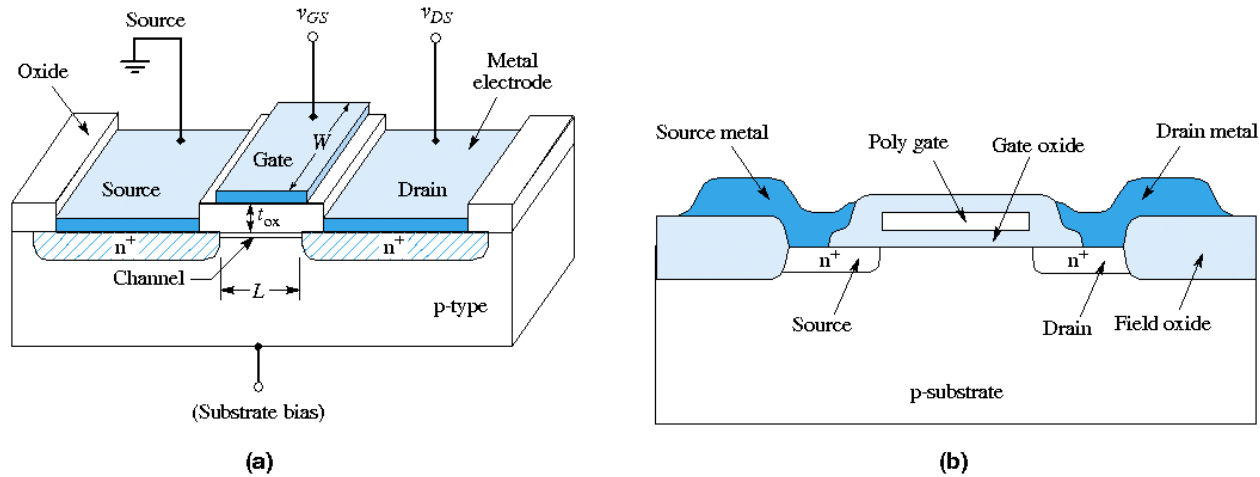


Figure 5.5 (a) Schematic diagram of an n-channel enhancement mode MOSFET and (b) an n-channel MOSFET, showing the field oxide and polysilicon gate

Transistor Operation

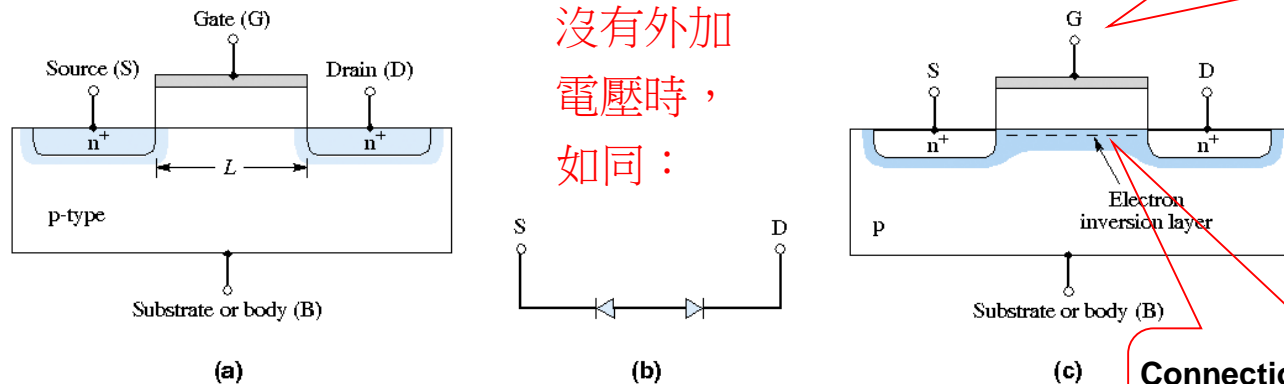


Figure 5.6 (a) Cross section of the n-channel MOSFET prior to the formation of an electron inversion layer, (b) equivalent back-to-back diodes between source and drain when the transistor is in cutoff, and (c) cross section after the formation of an electron inversion layer

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MOSFET Current-Voltage Characteristics

- ❑ The threshold voltage of the n-channel MOSFET is denoted as V_{TN} and is defined as the applied gate voltage needed to create an inversion charge.
- ❑ We can think of the threshold voltage as the gate voltage required to “turn on” the transistor.

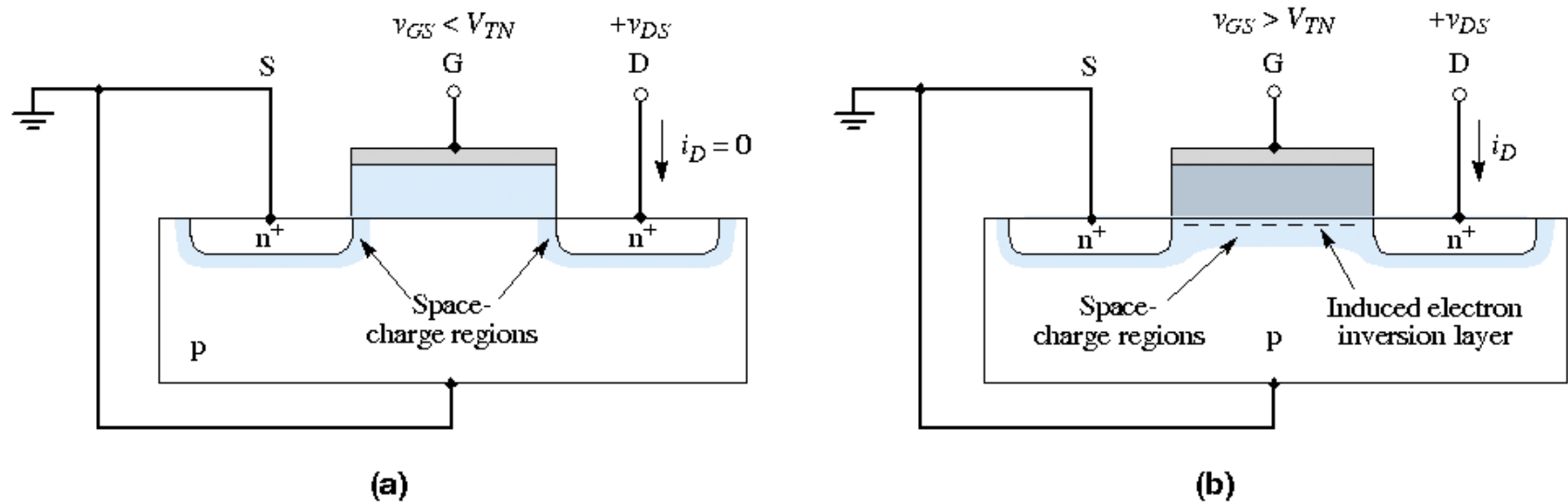


Figure 5.7 The n-channel enhancement-mode MOSFET (a) with an applied gate voltage $v_{GS} < V_{TN}$, and (b) with an applied gate voltage $v_{GS} > V_{TN}$

MOSFET Current-Voltage Characteristics

- The i_D versus v_{DS} characteristics for small values of v_{DS}

"當 v_{DS} 夠小時"， i_D 與 v_{DS} 關係圖，
 $v_{GS} > V_{TN}$ 時， i_D 會隨 v_{DS} 增加而增加。

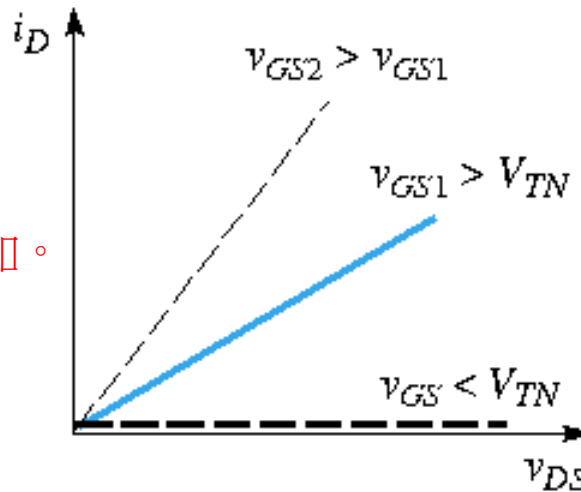


Figure 5.8 Plot of i_D versus v_{DS} characteristic for small values of v_{DS} at three v_{GS} voltages

MOSFET Current-Voltage Characteristics

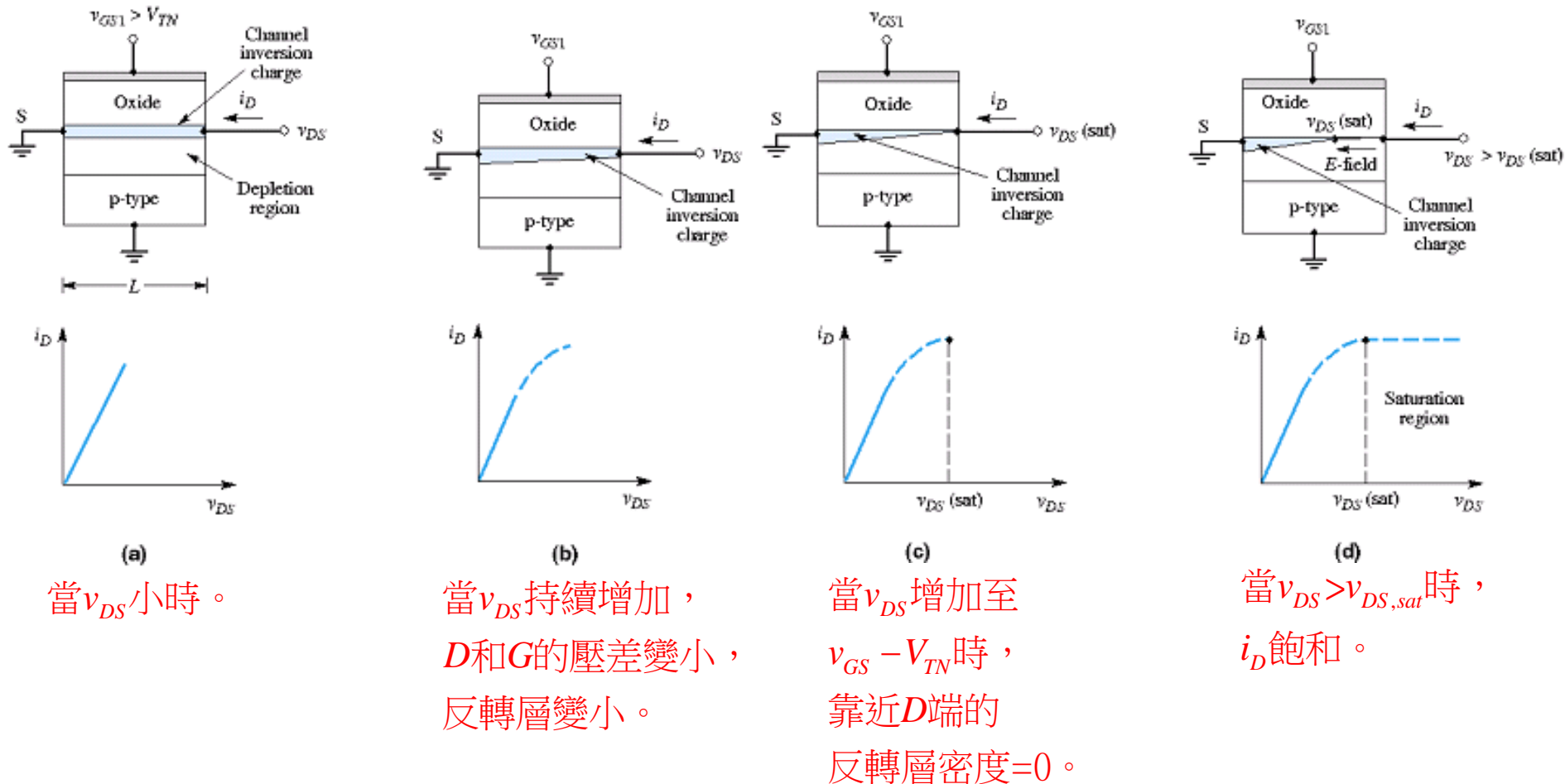


Figure 5.9 Cross section and i_D versus v_{DS} curve for an n-channel enhancement-mode MOSFET when $v_{GS} > V_{TN}$ for: (a) a small v_{DS} value, (b) a larger v_{DS} value, (c) $v_{DS} = v_{DS}(sat)$, and (d) $v_{DS} > v_{DS}(sat)$

Ideal MOSFET Current-Voltage Characteristics

□ Nonsaturation (triode) Region

形成電子反轉層 \Rightarrow NMOS

$$v_{DS} < v_{DS(sat)} = v_{GS} - V_{TN}$$

$$i_D = K_n [2(v_{GS} - V_{TN})v_{DS} - v_{DS}^2] = K_n (2v_{DS(sat)}v_{DS} - v_{DS}^2)$$

□ Saturation Region

$$v_{DS} > v_{DS(sat)} \quad (\text{also } v_{GS} > V_{TN})$$

$$i_D = K_n (v_{GS} - V_{TN})^2$$

Note: In the saturation region,

$$\frac{1}{r_o} = \partial i_D / \partial v_{DS} = \infty$$

$v_{GS} > V_{TN}$ 時，可分為

Nonsaturation & Saturation

反之，若 $v_{GS} < V_{TN}$ 時， $i_D = 0$ 。

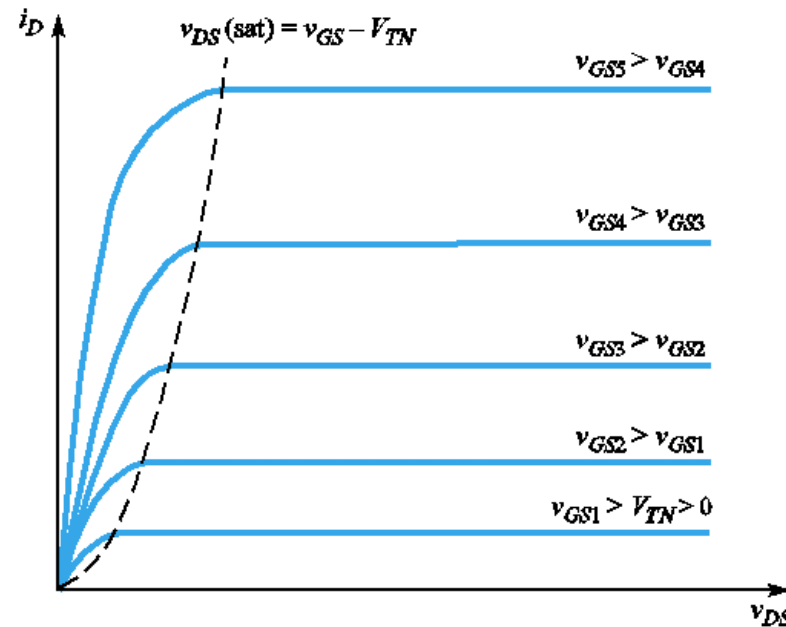


Figure 5.10 Family of i_D versus v_{DS} curves for an n-channel enhancement mode MOSFET

Conduction Parameter

□ Conduction Parameter

$$K_n = \frac{W}{L} \cdot \frac{\mu_n C_{ox}}{2} \quad (\text{conduction parameter})$$

C_{ox} : oxide capacitance per unit area $C_{ox} \propto \frac{1}{t_{ox}}$, t_{ox} : oxide thickness
 μ_n : electron mobility

W : channel width

L : channel length

□ The conduction parameter is a function of both electrical and geometric parameters.

- ✓ **Electrical Parameters:** The oxide capacitance and carrier mobility are essentially constants for a given technology.

$$K_n = \frac{W}{L} \cdot \frac{k'_n}{2} \quad k'_n : \text{constant} \quad k'_n = \mu_n C_{ox}$$

- ✓ **Geometrical Parameters:** The width-to-length ratio (W/L) is a variable in the design of MOSFETs that is used to produce specific current-voltage characteristics in MOSFET circuits. 可用以決定電流－電壓特性。

Example 5.1 Objective: Calculate the current in an n-channel MOSFET.

Consider an n-channel enhancement mode MOSFET with the following parameters: $V_{TN} = 0.75 \text{ V}$, $W = 40 \mu\text{m}$, $L = 4 \mu\text{m}$, $\mu_n = 650 \text{ cm}^2/\text{V-s}$, $t_{ox} = 450 \text{ \AA}$, and $\epsilon_{ox} = (3.9)(8.85 \times 10^{-14}) \text{ F/cm}$. Determine the current when $V_{GS} = 2V_{TN}$, for the transistor biased in the saturation region.

Solution:

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Solution:

$$K_n = \frac{W(\text{cm}) \cdot \mu_n \left(\frac{\text{cm}^2}{\text{V}\cdot\text{s}} \right) \epsilon_{ox} \left(\frac{\text{F}}{\text{cm}} \right)}{2L(\text{cm}) \cdot t_{ox}(\text{cm})} = \frac{\text{F}}{\text{V}\cdot\text{s}} = \frac{(\text{C/V})}{\text{V}\cdot\text{s}} = \frac{\text{A}}{\text{V}^2}$$

$$K_n = \frac{W \mu_n \epsilon_{ox}}{2L t_{ox}} = \frac{(40 \times 10^{-4})(650)(3.9)(8.85 \times 10^{-14})}{2(4 \times 10^{-4})(450 \times 10^{-8})}$$
$$= 0.249 \text{ mA/V}^2$$

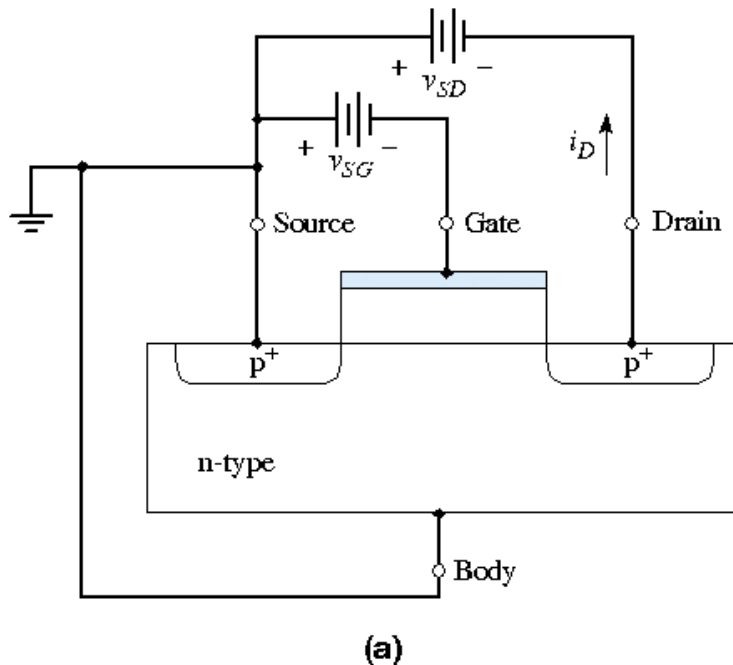
$$\text{For } v_{GS} = 2V_{TN}$$

$$i_D = K_n (v_{GS} - V_{TN})^2 = (0.249)(1.5 - 0.75)^2 = 0.140 \text{ mA}$$

Comment: The current capability of a transistor can be increased by increasing the conduction parameter. For a given fabrication technology, K_n is adjusted by varying the transistor width W .

形成電洞反轉層 \Rightarrow PMOS PMOS

- ❑ In the p-channel enhancement-mode device, a negative gate-to-source voltage must be applied to create the inversion layer of holes that connects the source and drain regions.
- ❑ The threshold voltage, denoted as V_{TP} for the PMOS is negative for an enhancement-mode devices. The threshold voltage is positive for a depletion-mode device.
- ❑ Holes flow from the source to the drain, the conventional current enters the source and leaves the drain.



- (1) G 與 D 要在低(負)電壓。
- (2) 形成電洞反轉層。
- (3) V_{TP} 為負值
- (4) 電流由 S 流向 D 。

Figure 5.15 Cross section of p-channel MOSFETs: (a) enhancement-mode and

Ideal PMOS Current-Voltage Relationship

□ Nonsaturation (triode) Region

when $v_{SD} < v_{SD(sat)} = v_{SG} + V_{TP}$:

$$i_D = K_p [2(v_{SG} + V_{TP})v_{SD} - v_{SD}^2] = K_p (2v_{SD(sat)}v_{SD} - v_{SD}^2)$$

□ Saturation Region

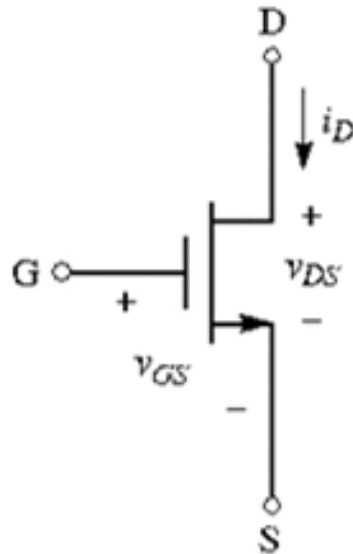
when $v_{SD} > v_{SD(sat)}$ (also $v_{SG} + V_{TP} > 0$) : $i_D = K_p (v_{SG} + V_{TP})^2$

$v_{SG} > -V_{TP}$ 時，可分為

Nonsaturation & Saturation

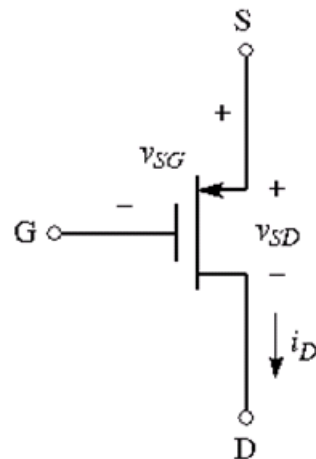
反之，若 $v_{SG} < -V_{TP}$ 時， $i_D = 0$ 。

Circuit Symbols



(b)

N-channel enhancement-mode MOSFET
(npn)



P-channel enhancement-mode MOSFET
(pnp)

Summary of MOS Transistor Operation

Table 5.1 Summary of the MOSFET current–voltage relationships

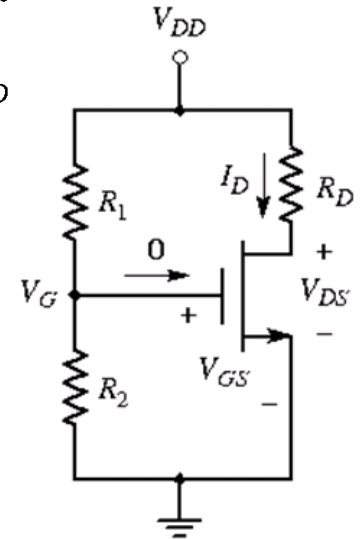
| NMOS | PMOS |
|------------------------------------------------------------------------------------------------------------|------------------------------------------------------------------------------------------------------------|
| Nonsaturation region ($v_{DS} < v_{DS}(\text{sat})$) $i_D = K_n[2(v_{GS} - V_{TN})v_{DS} - v_{DS}^2]$ | Nonsaturation region ($v_{SD} < v_{SD}(\text{sat})$) $i_D = K_p[2(v_{SG} + V_{TP})v_{SD} - v_{SD}^2]$ |
| Saturation region ($v_{DS} > v_{DS}(\text{sat})$) $i_D = K_n(v_{GS} - V_{TN})^2$ | Saturation region ($v_{SD} > v_{SD}(\text{sat})$) $i_D = K_p(v_{SG} + V_{TP})^2$ |
| Transition point $v_{DS}(\text{sat}) = v_{GS} - V_{TN}$ | Transition point $v_{SD}(\text{sat}) = v_{SG} + V_{TP}$ |
| Enhancement mode $V_{TN} > 0$ | Enhancement mode $V_{TP} < 0$ |

NMOS Common-Source Circuit

Example 5.3 Objective: Calculate the drain current and drain-to-source voltage of a common-source circuit with an n-channel enhancement-mode MOSFET.

For the circuit shown in Figure 5.24(a), assume that $R_1 = 30\text{ k}\Omega$, $R_2 = 20\text{ k}\Omega$, $R_D = 20\text{ k}\Omega$, $V_{DD} = 5\text{ V}$, $V_{TN} = 1\text{ V}$, and $K_n = 0.1\text{ mA/V}^2$.

Solution:



NMOS Common-Source Circuit

Example 5.3 Objective: Calculate the drain current and drain-to-source voltage of a common-source circuit with an n-channel enhancement-mode MOSFET.

For the circuit shown in Figure 5.24(a), assume that $R_1 = 30\text{ k}\Omega$, $R_2 = 20\text{ k}\Omega$, $R_D = 20\text{ k}\Omega$, $V_{DD} = 5\text{ V}$, $V_{TN} = 1\text{ V}$, and $K_n = 0.1\text{ mA/V}^2$.

Solution:

$$\textcircled{1} \quad V_G = V_{GS} = \left(\frac{R_2}{R_1 + R_2} \right) V_{DD} = \left(\frac{20}{20 + 30} \right) (5) = 2\text{ V}$$

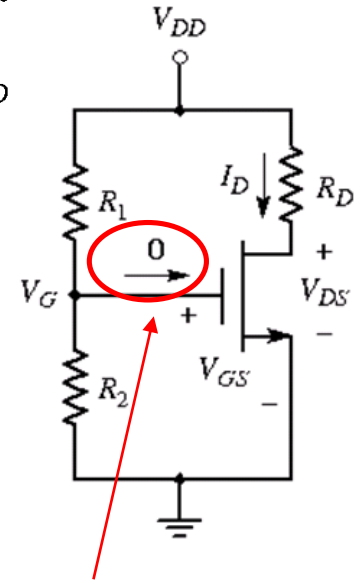
Assuming the transistor is biased in the saturation region, the drain current is

$$\textcircled{2} \quad I_D = K_n (V_{GS} - V_{TN})^2 = (0.1)(2 - 1)^2 = 0.1\text{ mA}$$

and the drain-to-source voltage is

$$\textcircled{3} \quad V_{DS} = V_{DD} - I_D R_D = 5 - (0.1)(20) = 3\text{ V}$$

$$\textcircled{4} \quad \text{Check } V_{DS} > V_{GS} - V_{TN} (= V_{DS,\text{sat}})$$



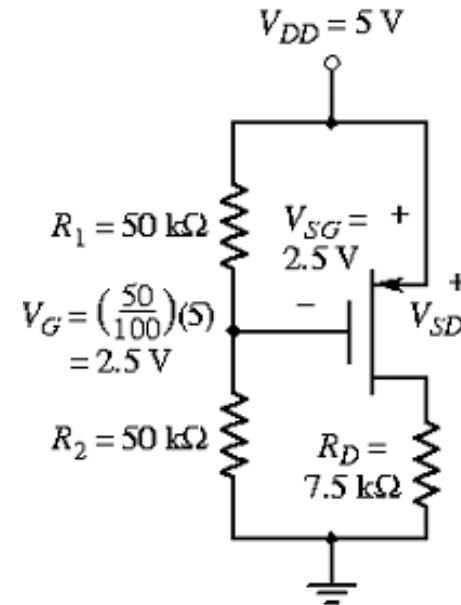
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PMOS Common-Source Circuit

Example 5.4 Objective: Calculate the drain current and source-to-drain voltage of a common-source circuit with a p-channel enhancement-mode MOSFET.

Consider the circuit shown in Figure 5.25(a). Assume that $R_1 = R_2 = 50 \text{ k}\Omega$, $V_{DD} = 5 \text{ V}$, $R_D = 7.5 \text{ k}\Omega$, $V_{TP} = -0.8 \text{ V}$, and $K_p = 0.2 \text{ mA/V}^2$.

Solution:



PMOS Common-Source Circuit

Example 5.4 Objective: Calculate the drain current and source-to-drain voltage of a common-source circuit with a p-channel enhancement-mode MOSFET.

Consider the circuit shown in Figure 5.25(a). Assume that $R_1 = R_2 = 50 \text{ k}\Omega$, $V_{DD} = 5 \text{ V}$, $R_D = 7.5 \text{ k}\Omega$, $V_{TP} = -0.8 \text{ V}$, and $K_p = 0.2 \text{ mA/V}^2$.

Solution:

$$\textcircled{1} \quad V_G = \left(\frac{R_2}{R_1 + R_2} \right) (V_{DD}) = \left(\frac{50}{50 + 50} \right) (5) = 2.5 \text{ V}$$

The source-to-gate voltage is therefore

$$\textcircled{2} \quad V_{SG} = V_{DD} - V_G = 5 - 2.5 = 2.5 \text{ V}$$

(a) Assuming the transistor is biased in the saturation region, the drain current is

$$I_D = K_p (V_{SG} + V_{TP})^2 = (0.2)(2.5 - 0.8)^2 = 0.578 \text{ mA}$$

and the source-to-drain voltage is

$$V_{SD} = V_{DD} - I_D R_D = 5 - (0.578)(7.5) = 0.665 \text{ V} < V_{SD, \text{sat}} = V_{SG} + V_{TP} = 2.5 - 0.8 = 1.7 \text{ V}$$

(假設矛盾)

(b) In the nonsaturation region, the drain current is given by

$$I_D = K_p \left[2(V_{SG} + V_{TP})\hat{V}_{SD} - \hat{V}_{SD}^2 \right]$$

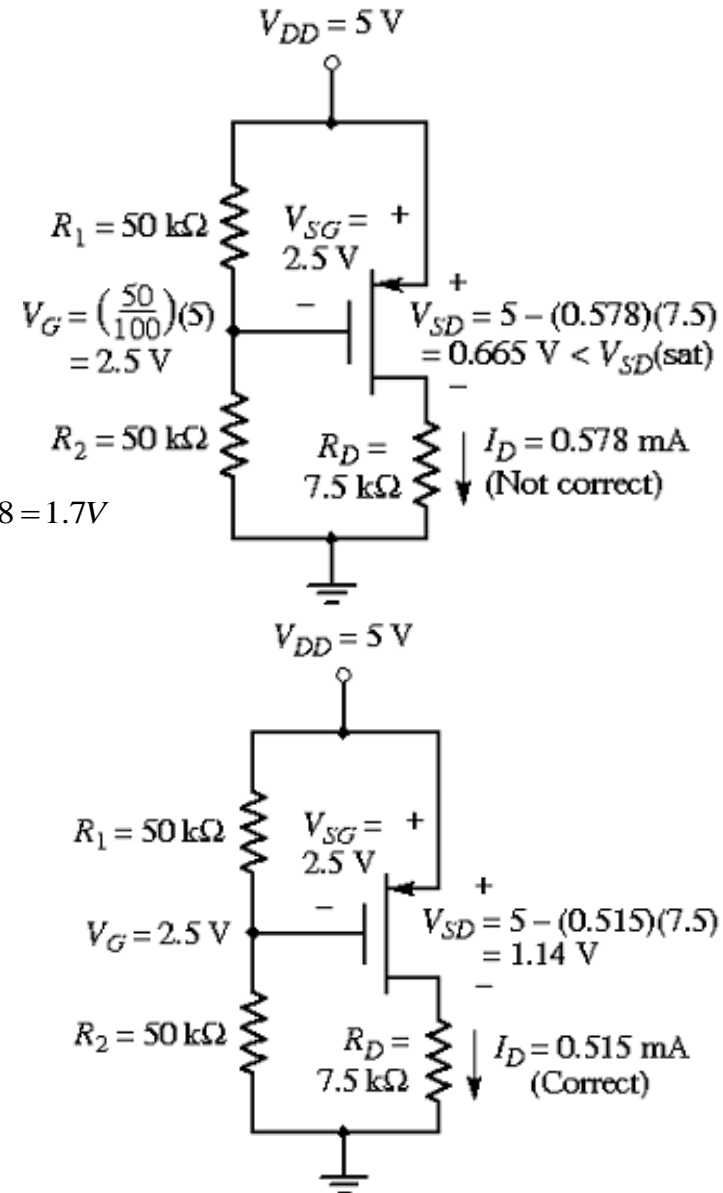
and the source-to-drain voltage is

$$V_{SD} = V_{DD} - I_D R_D$$

Combining these two equations, we obtain

$$\begin{aligned} I_D &= K_p \left[2(V_{SG} + V_{TP})(V_{DD} - I_D R_D) - (V_{DD} - I_D R_D)^2 \right] \\ &= (0.2) \left[2(2.5 - 0.8)(5 - I_D(7.5)) - (5 - I_D(7.5))^2 \right] \\ \Rightarrow I_D &= 0.515 \text{ mA} \end{aligned}$$

$$V_{SD} = 1.14 \text{ V} < V_{SD, \text{sat}} \quad (\text{假設成立})$$



DESIGN EXAMPLE 3.5

Objective: Design a MOSFET circuit biased with both positive and negative voltages to meet a set of specifications.

Specifications: The circuit configuration to be designed is shown in Figure 3.2. Design the circuit such that $I_{DQ} = 0.5 \text{ mA}$ and $V_{DSQ} = 4 \text{ V}$.

Choices: Standard resistors are to be used in the final design. A transistor with nominal parameters of $k'_n = 80 \mu\text{A/V}^2$, $(W/L) = 6.25$, and $V_{TN} = 1.2 \text{ V}$ is available. The parameters k'_n and V_{TN} may vary by ± 5 percent.

Solution:

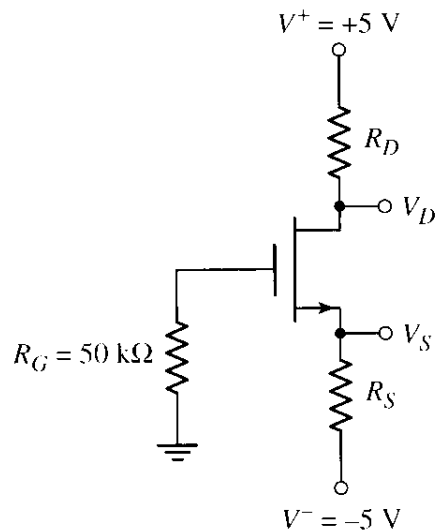


Figure 3.27 Circuit configuration for Example 3.5

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Solution:

(a) The conduction parameter: $K_n = \frac{k'_n}{2} \cdot \frac{W}{L} = \frac{0.080}{2} \cdot 6.25 = 0.25 \text{ mA/V}^2$

(b) Assume the transistor is biased in the saturation region

$$I_{DQ} = K_n (V_{GS} - V_{TN})^2 \Rightarrow V_{GS} = \sqrt{\frac{I_{DQ}}{K_n}} + V_{TN} = \sqrt{\frac{0.5}{0.25}} + 1.2 = 2.614 \text{ V}$$

(c) $I_G = 0 \Rightarrow V_G = 0 \Rightarrow V_{GS} = V_G - V_S = 0 - V_S \Rightarrow V_S = -V_{GS} = -2.614 \text{ V}$

(d) $V_S = V^- + I_{DQ}R_S \Rightarrow R_S = \frac{V_S - V^-}{I_{DQ}} = \frac{-2.614 - (-5)}{0.5} = 4.77 \text{ k}\Omega$

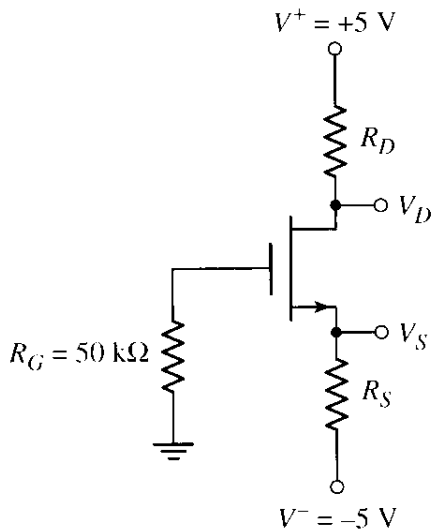


Figure 3.27 Circuit configuration for Example 3.5

$$(e) V_{DS} = V_D - V_S \Rightarrow V_D = V_S + V_{DS} = -2.614 + 4 = 1.386 \text{ V}$$

$$(f) V^+ = V_D + I_{DQ} R_D \Rightarrow R_D = \frac{V^+ - V_D}{I_{DQ}} = \frac{5 - 1.386}{0.5} = 7.23 \text{ k}\Omega$$

$$(g) \text{ Check: } V_{DS} = 4 \text{ V} > V_{DS,\text{sat}} = V_{GS} - V_{TN} = 2.61 - 1.2 = 1.41 \text{ V}$$

The transistor is indeed biased in the saturation region.

DESIGN EXAMPLE 3.6

Objective: Design a circuit with a p-channel MOSFET that is biased with both positive and negative voltage supplies to meet a set of specifications.

Specifications: The circuit to be designed is shown in Figure 3.30. Design the circuit such that $I_{DQ} = 100 \mu\text{A}$, $V_{SDQ} = 3 \text{ V}$, and $V_{RS} = 0.8 \text{ V}$. The value of the larger bias resistor, either R_1 or R_2 , is to be $200 \text{ k}\Omega$.

Choices: A transistor with parameters of $K_p = 100 \mu\text{A}/\text{V}^2$ and $V_{TP} = -0.4 \text{ V}$ is available. Standard resistor values are to be used in the final design.

Solution:

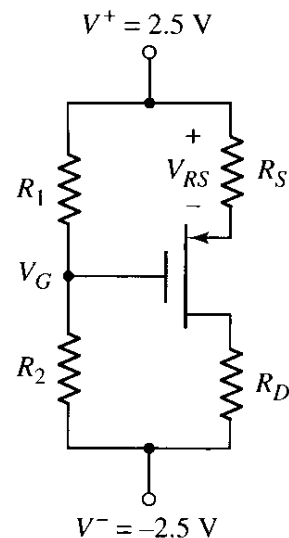


Figure 3.30 Circuit configuration for Example 3.6

DESIGN EXAMPLE 3.6

Objective: Design a circuit with a p-channel MOSFET that is biased with both positive and negative voltage supplies to meet a set of specifications.

Specifications: The circuit to be designed is shown in Figure 3.30. Design the circuit such that $I_{DQ} = 100 \mu\text{A}$, $V_{SDQ} = 3 \text{ V}$, and $V_{RS} = 0.8 \text{ V}$. The value of the larger bias resistor, either R_1 or R_2 , is to be $200 \text{ k}\Omega$.

Choices: A transistor with parameters of $K_p = 100 \mu\text{A}/\text{V}^2$ and $V_{TP} = -0.4 \text{ V}$ is available. Standard resistor values are to be used in the final design.

Solution:

(a) Assume the transistor is biased in the saturation region

$$I_{DQ} = K_p (V_{SG} + V_{TP})^2 \Rightarrow V_{SG} = \sqrt{\frac{I_{DQ}}{K_p}} - V_{TP} = \sqrt{\frac{100}{100}} - (-0.4) = 1.4 \text{ V}$$

(b) $V_G = V^+ - V_{RS} - V_{SG} = 2.5 - 0.8 - 1.4 = 0.3 \text{ V}$

(c) Since $V_G = 0.3 \text{ V} > 0 \text{ V}$, R_2 is chosen as $200 \text{ k}\Omega$.

(d) $I_{Bias} = I_{R_2} = \frac{V_G - V^-}{R_2} = \frac{0.3 - (-2.5)}{200} = 0.014 \text{ mA}$

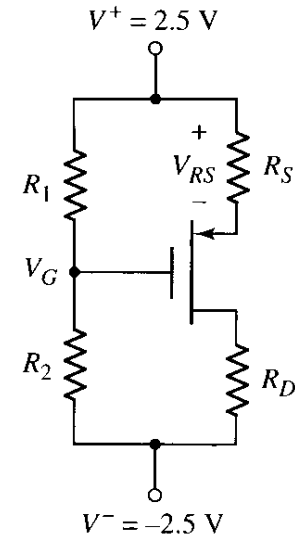


Figure 3.30 Circuit configuration for Example 3.6

$$(e) V^+ = V_G + I_{Bias} R_1 \Rightarrow R_1 = \frac{V^+ - V_G}{I_{Bias}} = \frac{2.5 - 0.3}{0.014} = 157 \text{ k}\Omega$$

$$(f) R_S = \frac{V_{RS}}{I_{DQ}} = \frac{0.8}{0.1} = 8 \text{ k}\Omega$$

$$(g) V_D = V^+ - V_{RS} - V_{SD} = 2.5 - 0.8 - 3 = -1.3 \text{ V}$$

$$(h) R_D = \frac{V_D - V^-}{I_{DQ}} = \frac{-1.3 - (-2.5)}{0.1} = 12 \text{ k}\Omega$$

$$(i) \text{ Check: } V_{SD} = 3 \text{ V} > V_{SD,\text{sat}} = V_{SG} + V_{TP} = 1.4 + (-0.4) = 1 \text{ V}$$

The transistor is indeed biased in the saturation region.

Load Line

□ Load Line

$$V_{DS} = V_{DD} - I_D R_D = 5 - I_D (20)$$

$$I_D = \frac{5}{20} - \frac{V_{DS}}{20} \text{ (mA)}$$

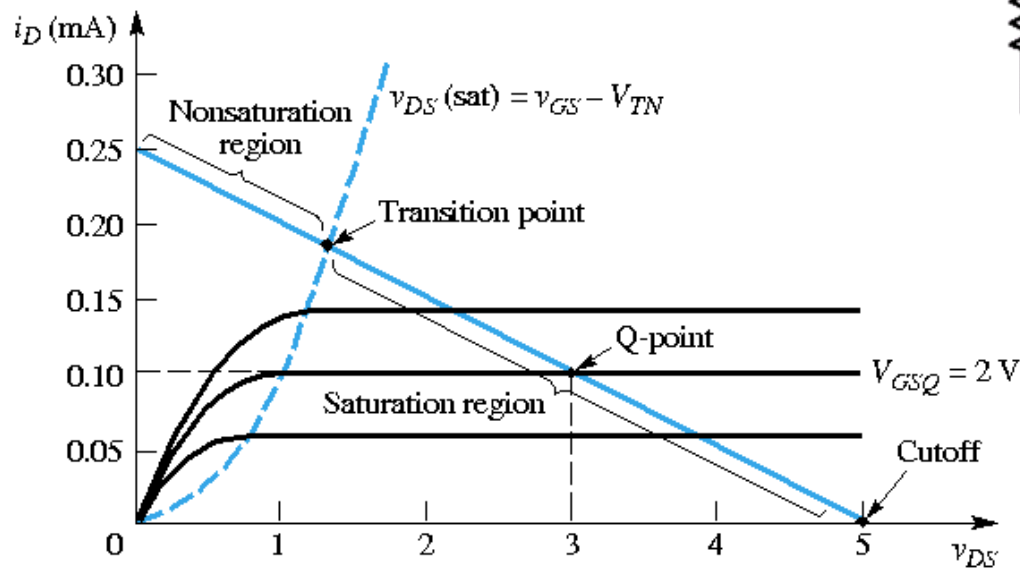
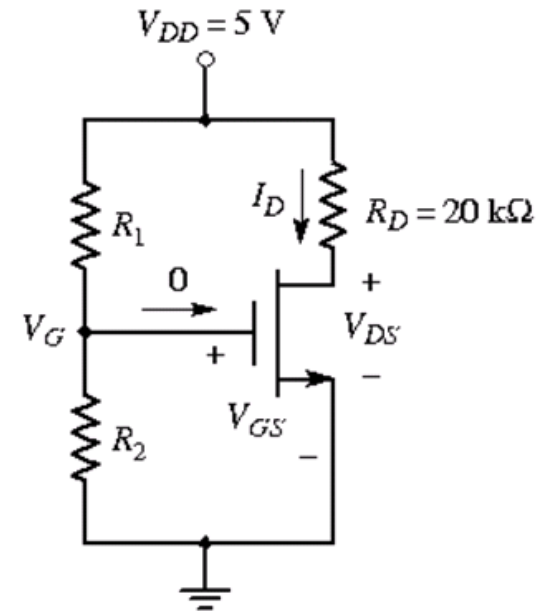
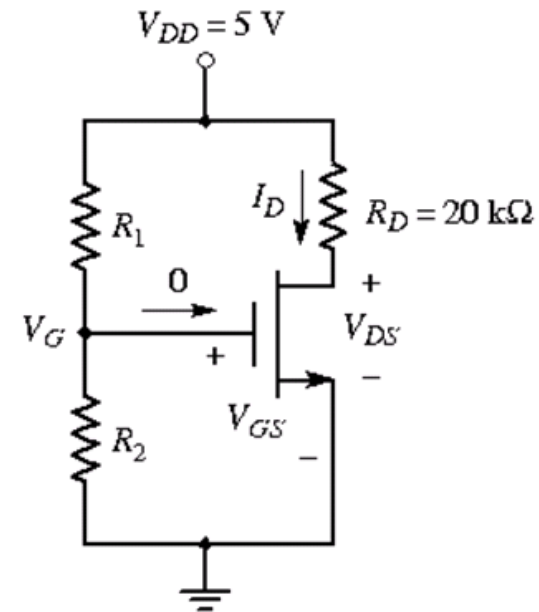


Figure 5.28 Transistor characteristics, $v_{DS}(\text{sat})$ curve, load line, and Q -point for the NMOS common-source circuit in Figure 5.24(b)

Example 5.5 Objective: Determine the transition point parameters for a common-source circuit.

Consider the circuit shown in Figure 5.24(b). Assume transistor parameters of $V_{TN} = 1\text{ V}$ and $K_n = 0.1\text{ mA/V}^2$.

Solution:



Example 5.5 Objective: Determine the transition point parameters for a common-source circuit.

Consider the circuit shown in Figure 5.24(b). Assume transistor parameters of $V_{TN} = 1\text{ V}$ and $K_n = 0.1\text{ mA/V}^2$.

Solution:

$$(a) V_{DS} = V_{DS}(\text{sat}) = V_{GS} - V_{TN} = V_{DD} - I_D R_D$$

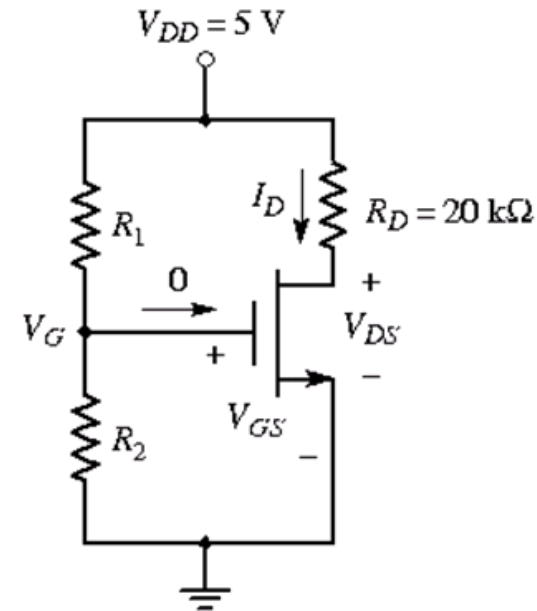
$$(b) I_D = K_n (V_{GS} - V_{TN})^2$$

From (a) and (b), we can get

$$\begin{aligned} (c) V_{GS} - V_{TN} &= V_{DD} - K_n R_D (V_{GS} - V_{TN})^2 \\ \Rightarrow K_n R_D (V_{GS} - V_{TN})^2 + (V_{GS} - V_{TN}) - V_{DD} &= 0 \\ \Rightarrow (0.1)(20)(V_{GS} - V_{TN})^2 + (V_{GS} - V_{TN}) - 5 &= 0 \\ \Rightarrow V_{GS} - V_{TN} = 1.35\text{ V} = V_{DS} \end{aligned}$$

$$(d) V_{GS} = 2.35\text{ V}$$

$$(e) I_D = (0.1)(2.35 - 1)^2 = 0.182\text{ mA}$$



DESIGN EXAMPLE 3.8

Objective: Design the dc bias of a MOSFET circuit to meet a set of specifications.

Specifications: The circuit configuration to be designed is shown in Figure 3.34. The quiescent Q -point values are to be $I_{DQ} = 0.25 \text{ mA}$ and $V_{DSQ} = 4 \text{ V}$. The voltage across R_S should be $V_{RS} \cong 1 \text{ V}$. The current in the bias resistors should be approximately $20 \mu\text{A}$.

Choices: Discrete resistors are to be used in the final design. A transistor with parameters of $k'_n = 80 \mu\text{A/V}^2$, $W/L = 4$, and $V_{TN} = 1.2 \text{ V}$ is available. The resistors R_D and R_S have tolerances of ± 10 percent.

Solution:

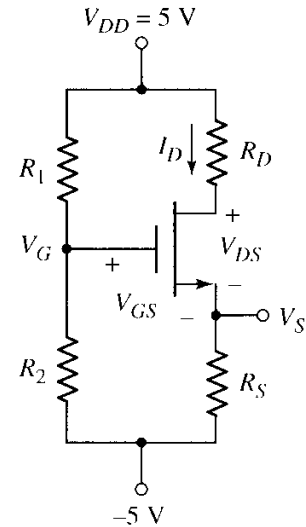


Figure 3.34 NMOS common-source circuit with source resistor

DESIGN EXAMPLE 3.8

Objective: Design the dc bias of a MOSFET circuit to meet a set of specifications.

Specifications: The circuit configuration to be designed is shown in Figure 3.34. The quiescent Q -point values are to be $I_{DQ} = 0.25 \text{ mA}$ and $V_{DSQ} = 4 \text{ V}$. The voltage across R_S should be $V_{RS} \cong 1 \text{ V}$. The current in the bias resistors should be approximately $20 \mu\text{A}$.

Choices: Discrete resistors are to be used in the final design. A transistor with parameters of $k'_n = 80 \mu\text{A/V}^2$, $W/L = 4$, and $V_{TN} = 1.2 \text{ V}$ is available. The resistors R_D and R_S have tolerances of ± 10 percent.

Solution:

$$(a) R_S = \frac{V_{RS}}{I_{DQ}} = \frac{1}{0.25} = 4 \text{ k}\Omega$$

$$\begin{aligned} (b) 5 &= I_{DQ}R_D + V_{DS} + I_{DQ}R_S - 5 \\ \Rightarrow 5 &= (0.25)R_D + 4 + (0.25)(4) - 5 \\ \Rightarrow R_D &= 20 \text{ k}\Omega \end{aligned}$$

$$\begin{aligned} (c) 5 - (-5) &= I_{Bias} \times (R_1 + R_2) \\ \Rightarrow R_1 + R_2 &= \frac{5 + 5}{0.020} = 500 \text{ k}\Omega \end{aligned}$$

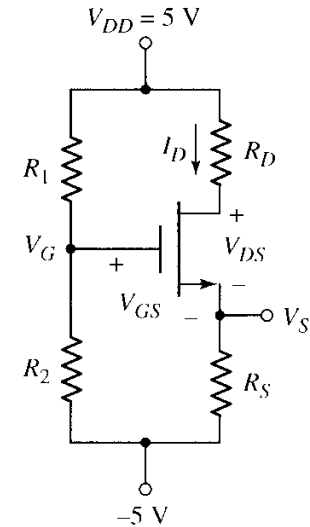


Figure 3.34 NMOS common-source circuit with source resistor

(d) Assume the transistor is in the saturation region

$$I_D = \frac{k'_n}{2} \frac{W}{L} (V_{GS} - V_{TN})^2$$
$$\Rightarrow 0.25 = \frac{0.080}{2} \cdot 4(V_{GS} - 1.2)^2$$
$$\Rightarrow V_{GS} = 2.45 \text{ V}$$

(e) $V_{GS} = V_G - V_S = \left[\left(\frac{R_2}{R_1 + R_2} \right) (10) - 5 \right] - [I_D R_S - 5]$

$$\Rightarrow 2.45 = \left[\left(\frac{R_2}{500} \right) (10) - 5 \right] - [(0.25)(4) - 5]$$
$$\Rightarrow R_2 = 172.5 \text{ k}\Omega$$

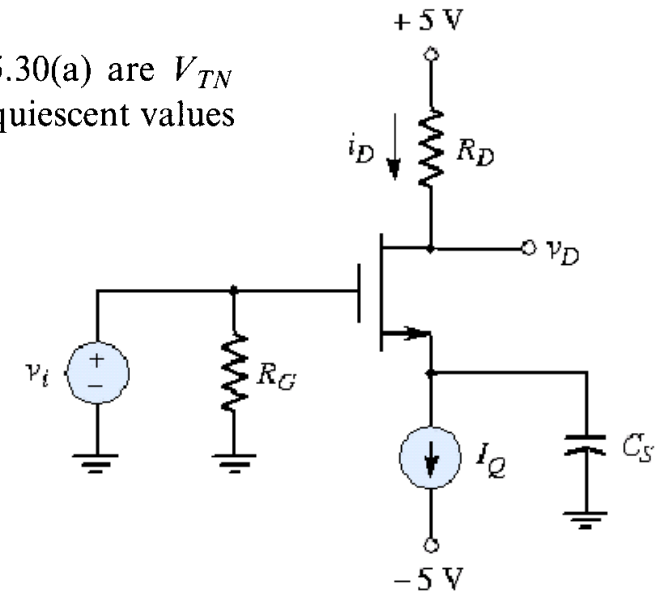
(f) From (c) and (e), we can get

$$R_1 = 327.5 \text{ k}\Omega$$

Design Example 5.7 Objective: Design a MOSFET circuit biased with a constant-current source.

The parameters of the transistor in the circuit shown in Figure 5.30(a) are $V_{TN} = 0.8\text{ V}$, $k'_n = 80\text{ }\mu\text{A/V}^2$, and $W/L = 3$. Design the circuit such that the quiescent values are $I_D = 250\text{ }\mu\text{A}$ and $V_D = 2.5\text{ V}$.

Solution:



(a)

Design Example 5.7 Objective: Design a MOSFET circuit biased with a constant-current source.

The parameters of the transistor in the circuit shown in Figure 5.30(a) are $V_{TN} = 0.8 \text{ V}$, $k'_n = 80 \mu\text{A}/\text{V}^2$, and $W/L = 3$. Design the circuit such that the quiescent values are $I_D = 250 \mu\text{A}$ and $V_D = 2.5 \text{ V}$.

Solution:

(a) The DC equivalent circuit is shown in Fig (b) by setting $v_i = 0$.

(b) Assume the transistor is in the saturation region

$$I_D = \frac{k'_n}{2} \frac{W}{L} (V_{GS} - V_{TN})^2$$

$$\Rightarrow 250 = \left(\frac{80}{2} \right) \cdot (3) (V_{GS} - 0.8)^2$$

$$\Rightarrow V_{GS} = 2.24 \text{ V}$$

(c) $V_{GS} = V_G - V_S = 0 - V_S = 2.24 \text{ V}$

$$\Rightarrow V_S = -2.24 \text{ V}$$

(d) $V_D + I_D R_D = 5$

$$\Rightarrow 2.5 + (0.25) R_D = 5$$

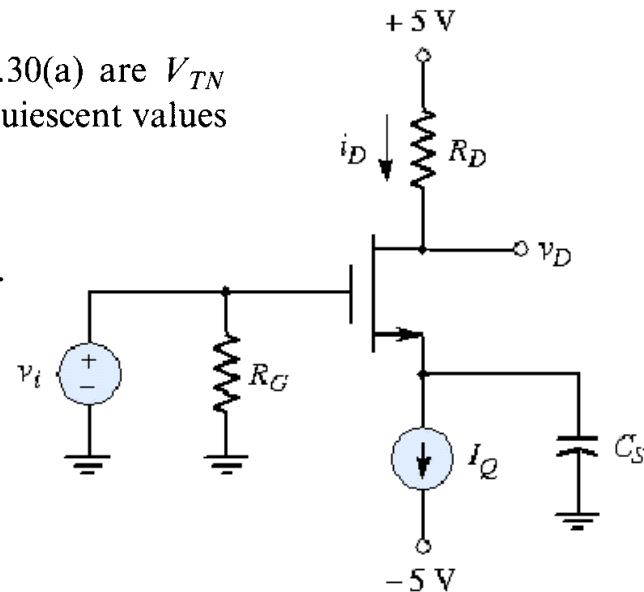
$$\Rightarrow R_D = 10 \text{ k}\Omega$$

(e) $V_{DS} = V_D - V_S = 2.5 - (-2.24) = 4.74 \text{ V}$

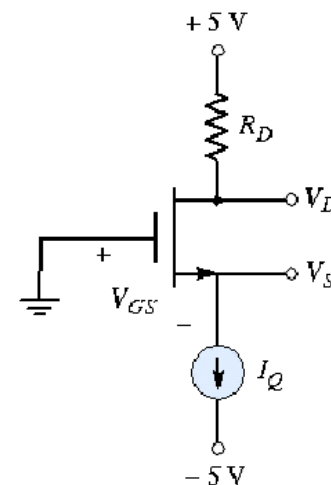
(f) Check: $V_{DS} = V_D - V_S = 2.5 - (-2.24) = 4.74 \text{ V}$

$$V_{DS, \text{sat}} = V_{GS} - V_{TN} = 2.24 - 0.8 = 1.44 \text{ V}$$

$V_{DS} > V_{DS, \text{sat}} \Rightarrow$ The transistor is biased in the saturation region.



(a)



(b)

Nonlinear Resistor

- ❑ An enhancement-mode MOSFET is used as a nonlinear resistor.
- ❑ The transistor is always biased in the saturation region and called a load device.

$$v_{DS} = v_{GS} > v_{DS(sat)} = v_{GS} - V_{TN}, \quad V_{TN} > 0$$

$$i_D = K_n (v_{GS} - V_{TN})^2 = K_n (v_{DS} - V_{TN})^2$$

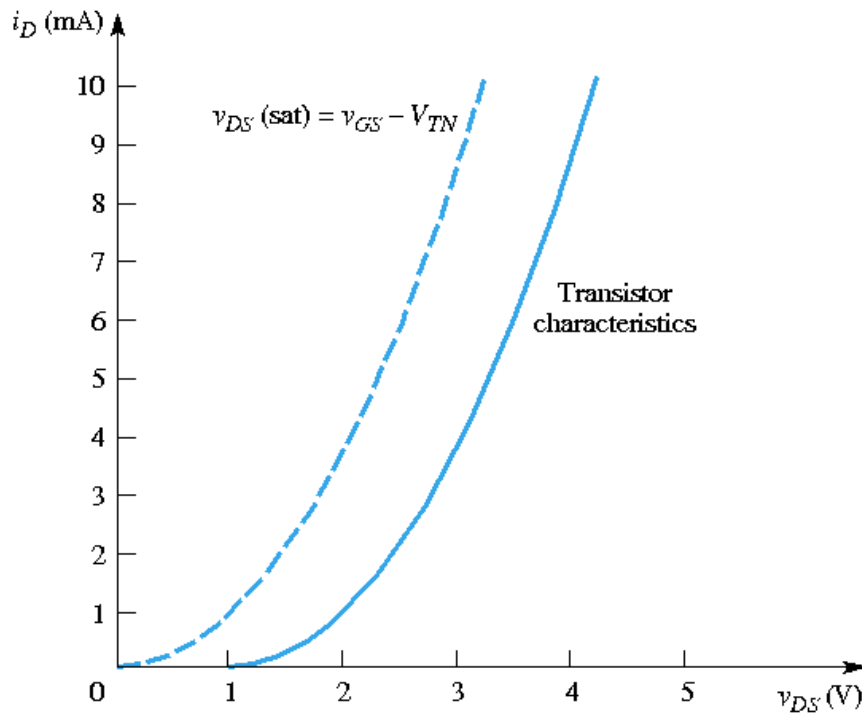


Figure 5.33 Current-voltage characteristic of an enhancement load device

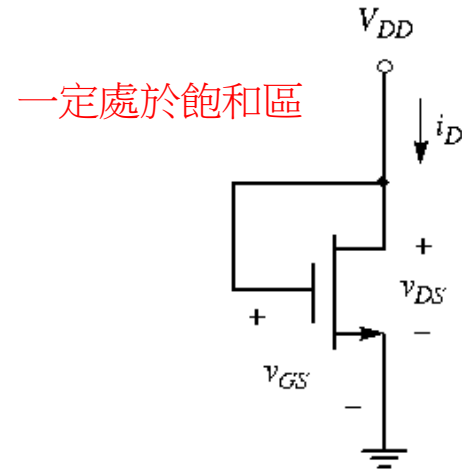


Figure 5.32 Enhancement-mode NMOS device with the gate connected to the drain

Example 5.8 Objective: Calculate the characteristics of a circuit containing an enhancement load device.

Consider the circuit shown in Figure 5.34 with transistor parameters $V_{TN} = 0.8\text{ V}$ and $K_n = 0.05\text{ mA/V}^2$.

Solution:

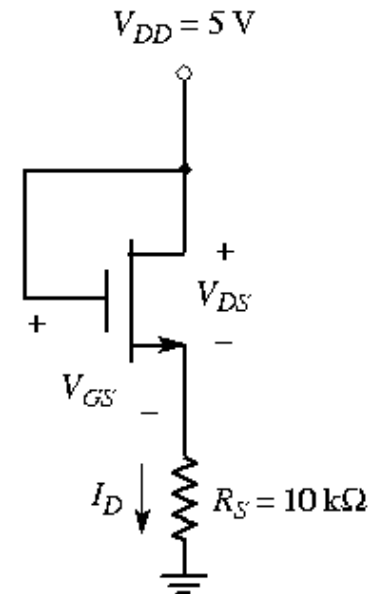


Figure 5.34 Circuit containing an enhancement load device

Example 5.8 Objective: Calculate the characteristics of a circuit containing an enhancement load device.

Consider the circuit shown in Figure 5.34 with transistor parameters $V_{TN} = 0.8 \text{ V}$ and $K_n = 0.05 \text{ mA/V}^2$.

Solution:

(a) The transistor must be based in the saturation region

$$I_D = K_n (V_{GS} - V_{TN})^2$$

(b) $V_{DS} = V_{GS} = 5 - I_D R_S$

(c) From (a) and (b), we can get

$$V_{GS} = 5 - K_n R_S (V_{GS} - V_{TN})^2$$

$$\Rightarrow V_{GS} = 5 - (0.05)(10)(V_{GS} - 0.8)^2$$

$$\Rightarrow V_{GS} = -3.27 \text{ V (矛盾, } V_{GS} < V_{TN}) \text{ or } V_{GS} = +2.87 \text{ V}$$

(d) $V_{GS} = V_{DS} = 2.87 \text{ V}$ and $I_D = 0.213 \text{ mA}$

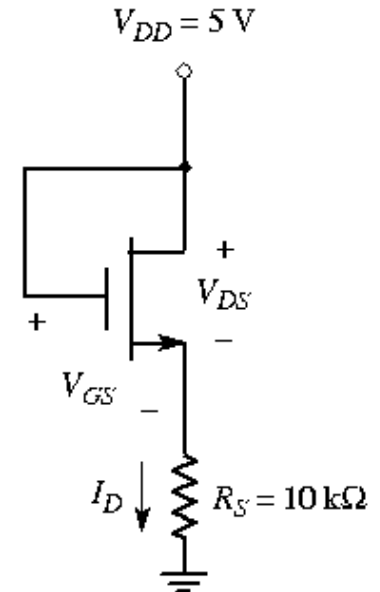
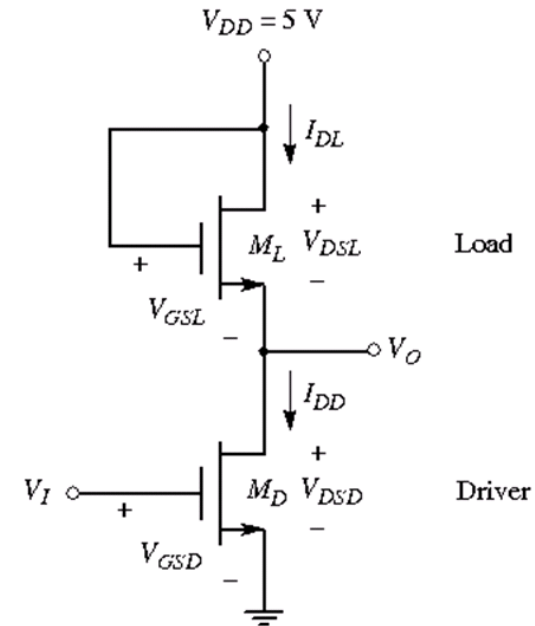


Figure 5.34 Circuit containing an enhancement load device

Example 5.9 Objective: Determine the dc transistor currents and voltages in a circuit containing an enhancement load device.

The transistors in the circuit shown in Figure 5.35 have parameters $V_{TND} = V_{TNL} = 1\text{ V}$, $K_{nD} = 50\text{ }\mu\text{A/V}^2$, and $K_{nL} = 10\text{ }\mu\text{A/V}^2$. (The subscript D applies to the driver transistor and the subscript L applies to the load transistor.) Determine V_O for $V_I = 5\text{ V}$ and $V_I = 1.5\text{ V}$.

Solution:



Example 5.9 Objective: Determine the dc transistor currents and voltages in a circuit containing an enhancement load device.

The transistors in the circuit shown in Figure 5.35 have parameters $V_{TND} = V_{TNL} = 1\text{ V}$, $K_{nD} = 50\text{ }\mu\text{A/V}^2$, and $K_{nL} = 10\text{ }\mu\text{A/V}^2$. (The subscript D applies to the driver transistor and the subscript L applies to the load transistor.) Determine V_O for $V_I = 5\text{ V}$ and $V_I = 1.5\text{ V}$.

Solution:

(1) $V_I = 5\text{ V}$

(a) Assume that the transistor M_D is biased in the non-saturation region.

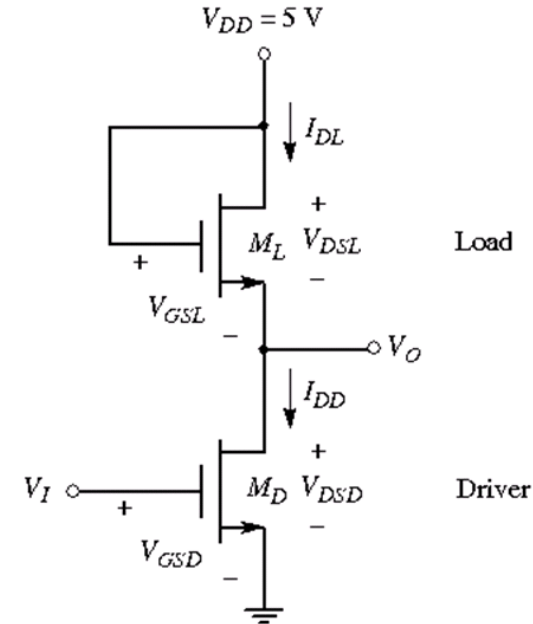
$$\begin{aligned}
 I_{DD} &= I_{DL} \\
 \Rightarrow K_{nD} [2(V_{GSD} - V_{TND})V_{DSD} - V_{DSD}^2] &= K_{nL} [V_{GSL} - V_{TNL}]^2 \\
 \Rightarrow K_{nD} [2(V_I - V_{TND})V_O - V_O^2] &= K_{nL} [V_{DD} - V_O - V_{TNL}]^2 \\
 \Rightarrow (50) [2(5 - 1)V_O - V_O^2] &= (10) [5 - V_O - 1]^2 \\
 \Rightarrow 3V_O^2 - 24V_O + 8 &= 0 \\
 \Rightarrow V_O = 7.65\text{ V (矛盾, } V_O > V_{DD}) \text{ or } V_O &= 0.349\text{ V}
 \end{aligned}$$

$$\begin{aligned}
 \text{(b) } I_D &= K_{nL} (V_{GSL} - V_{TNL})^2 = K_{nL} (V_{DD} - V_O - V_{TNL})^2 \\
 \Rightarrow I_D &= (10)(5 - 0.349 - 1)^2 = 133\text{ }\mu\text{A}
 \end{aligned}$$

(c) Check: $V_{DS} = V_O = 0.349\text{ V}$

$$V_{DS,sat} = V_{GS} - V_{TN} = 5 - 1 = 4\text{ V}$$

$V_{DS} < V_{DS,sat} \Rightarrow$ The transistor M_D is biased in the non-saturation region.



(2) $V_I = 1.5\text{V}$

(a) Assume that the transistor M_D is biased in the saturation region.

$$I_{DD} = I_{DL}$$

$$\Rightarrow K_{nD} [V_{GSD} - V_{TND}]^2 = K_{nL} [V_{GSL} - V_{TNL}]^2$$

$$\Rightarrow K_{nD} [V_I - V_{TND}]^2 = K_{nL} [V_{DD} - V_O - V_{TNL}]^2$$

$$\Rightarrow \sqrt{50} [1.5 - 1] = \sqrt{10} [5 - V_O - 1]$$

(b) $I_D = K_{nD} (V_{GSD} - V_{TND})^2 = (50)(1.5 - 1)^2 = 12.5 \mu\text{A}$

(c) Check: $V_{DS} = V_O = 2.88\text{V}$

$$V_{DS,sat} = V_{GS} - V_{TN} = 1.5 - 1 = 0.5\text{V}$$

$V_{DS} > V_{DS,sat} \Rightarrow$ The transistor M_D is biased the saturation region.

NMOS Inverter

- If $v_I < V_{TN}$, the transistor is in cut-off.

$$i_D = 0$$
$$v_O = V_{DD}$$

- If $v_I > V_{TN}$ (and make $v_I - V_{TN} > v_{DS}$), the transistor is biased in the non-saturation region.

$$i_D = K_n [2(v_I - V_{TN})v_O - v_O^2]$$
$$v_O = v_{DD} - i_D R_D$$

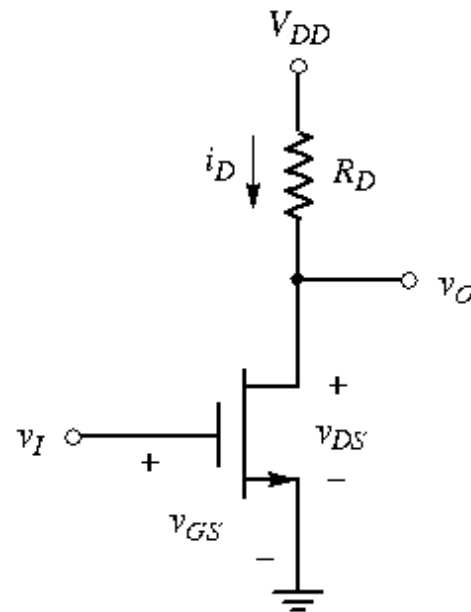
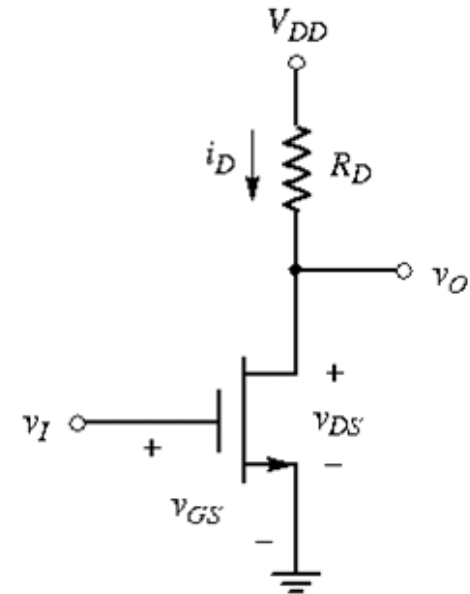


Figure 5.44 NMOS inverter circuit

Design Example 5.14 Objective: Design the size of a power MOSFET to meet the specification of a particular switch application.

The load in the inverter circuit in Figure 5.44 is a coil of an electromagnet that requires a current of 0.5 A when turned on. The effective load resistance varies between 8 and 10 Ω , depending on temperature and other variables. A 10 V power supply is available. The transistor parameters are $k'_n = 80 \mu\text{A}/\text{V}^2$ and $V_{TN} = 1 \text{ V}$.

Solution:



Design Example 5.14 Objective: Design the size of a power MOSFET to meet the specification of a particular switch application.

The load in the inverter circuit in Figure 5.44 is a coil of an electromagnet that requires a current of 0.5 A when turned on. The effective load resistance varies between 8 and 10 Ω , depending on temperature and other variables. A 10 V power supply is available. The transistor parameters are $k'_n = 80 \mu\text{A}/\text{V}^2$ and $V_{TN} = 1 \text{ V}$.

Solution:

(a) The solution is to bias the transistor in the saturation region.

\Rightarrow The current is constant, independent of the load resistance.

$$(b) V_0 = V_{DD} - I_D R_D = \begin{cases} 10 - 0.5 \times 8 = 6\text{V} \\ 10 - 0.5 \times 10 = 5\text{V} \end{cases}$$

$$V_{DS,\min} = 5\text{V}$$

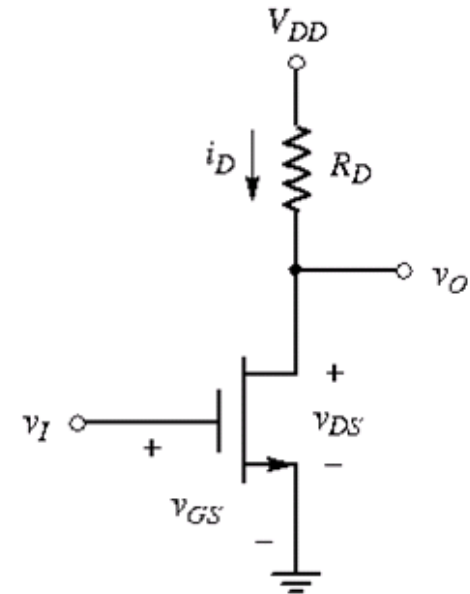
(c) Need $V_{DS,\min} \geq V_{DS,\text{sat}} = V_{GS} - V_{TN}$

\Rightarrow Always in the saturation region

Choose $V_{GS} = 5\text{V}$

$$(d) I_D = \frac{k'_n}{2} \frac{W}{L} (V_{GS} - V_{TN})^2$$

$$\Rightarrow 0.5 = \frac{80 \times 10^{-6}}{2} \frac{W}{L} (5 - 1)^2 \Rightarrow \frac{W}{L} = 781$$

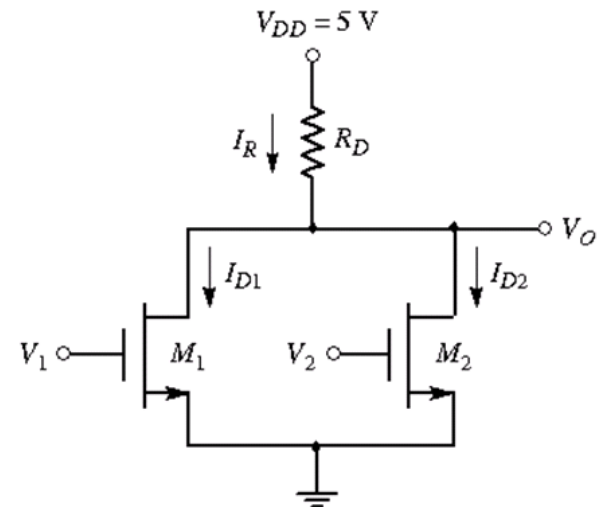


Digital Logic Gate

Example 5.15 Objective: Determine the currents and voltages in a digital logic gate, for various input conditions.

Consider the circuit shown in Figure 5.46 with circuit and transistor parameters $R_D = 20 \text{ k}\Omega$, $K_n = 0.1 \text{ mA/V}^2$, and $V_{TN} = 0.8 \text{ V}$.

Solution:



Digital Logic Gate

Digital Logic Gate

Example 5.15 Objective: Determine the currents and voltages in a digital logic gate, for various input conditions.

Consider the circuit shown in Figure 5.46 with circuit and transistor parameters $R_D = 20 \text{ k}\Omega$, $K_n = 0.1 \text{ mA/V}^2$, and $V_{TN} = 0.8 \text{ V}$.

Solution:

(a) $V_1 = V_2 = 0 \text{ V} \Rightarrow M_1, M_2$ are both cut off

$$V_0 = V_{DD} = 5 \text{ V}$$

(b) $V_1 = 5 \text{ V}, V_2 = 0 \text{ V}$

$\Rightarrow M_2$ is cut off, $I_{D2} = 0$

(1) Assume M_1 is in the saturation region

$$I_{D1} = K_n (V_{GS1} - V_{TN})^2 = 0.1(5 - 0.8)^2 = 1.764 \text{ mA}$$

$$I_R = I_{D1} + I_{D2} = I_{D1}$$

$$V_{DS1} = V_0 = V_{DD} - I_R R_D = 5 - 1.764 \times 20 = 1.8 \text{ V}$$

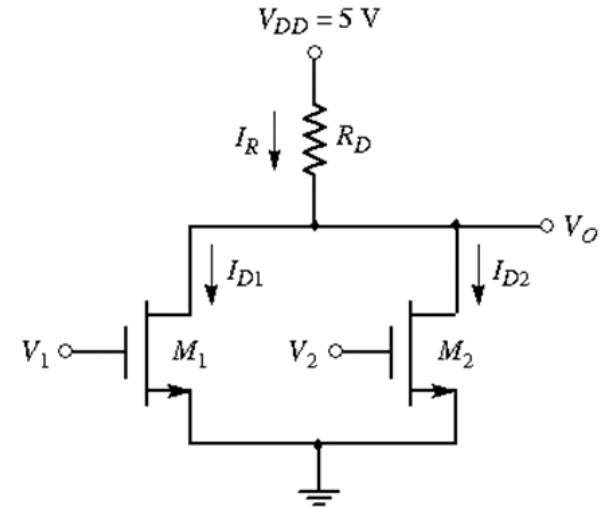
$$V_{DS1} < V_{DS1,\text{sat}} = V_{GS1} - V_{TN} = 4.2 \text{ V} \quad (\text{假設矛盾})$$

(2) Assume M_1 is in the non-saturation region

$$I_R = I_{D1} \Rightarrow \frac{5 - V_0}{R_D} = K_n [2(V_1 - V_{TN})V_0 - V_0^2]$$

$$V_0 = 0.29 \text{ V} = V_{DS1}, \quad I_R = I_{D1} = \frac{5 - V_0}{R_D} = \frac{5 - 0.29}{20} = 0.236 \text{ mA}$$

$$V_{DS1} < V_{DS1,\text{sat}} = V_{GS1} - V_{TN} = 4.2 \text{ V} \quad (\text{假設成立})$$



Digital Logic Gate

(c) $V_1 = 0\text{V}, V_2 = 5\text{V}$

M_1 is cut off, $I_{D1} = 0$

M_2 is in the non-saturation region

$$\Rightarrow V_0 = 0.29\text{V}, I_R = I_{D2} = 0.236\text{mA}$$

(d) $V_1 = 5\text{V}, V_2 = 5\text{V}$

M_1 and M_2 are both in the non-saturation region

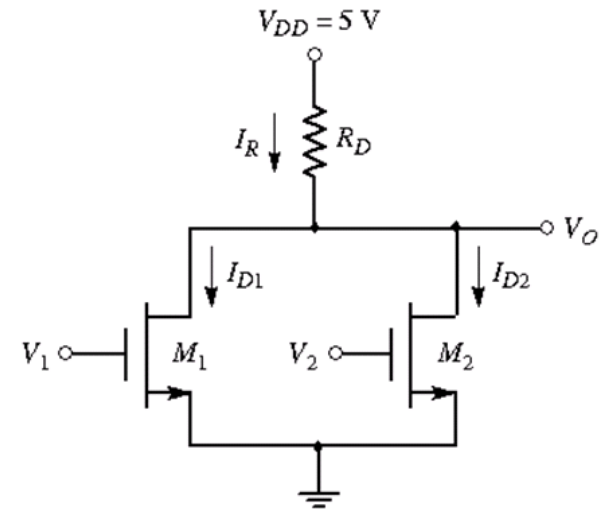
$$I_R = I_{D1} + I_{D2}$$

$$\Rightarrow \frac{5 - V_0}{R_D} = K_n \left[2(V_1 - V_{TN})V_0 - V_0^2 \right] + K_n \left[2(V_2 - V_{TN})V_0 - V_0^2 \right]$$

$$\Rightarrow V_0 = 0.147\text{V}$$

$$I_R = \frac{5 - 0.147}{20} = 0.243\text{mA}$$

$$I_{D1} = I_{D2} = \frac{I_R}{2} = 0.121\text{mA}$$



MOS Small-Signal Amplifier

- We can establish a particular Q-point on the load line by designing the ratio of the bias resistors R_1 and R_2 .

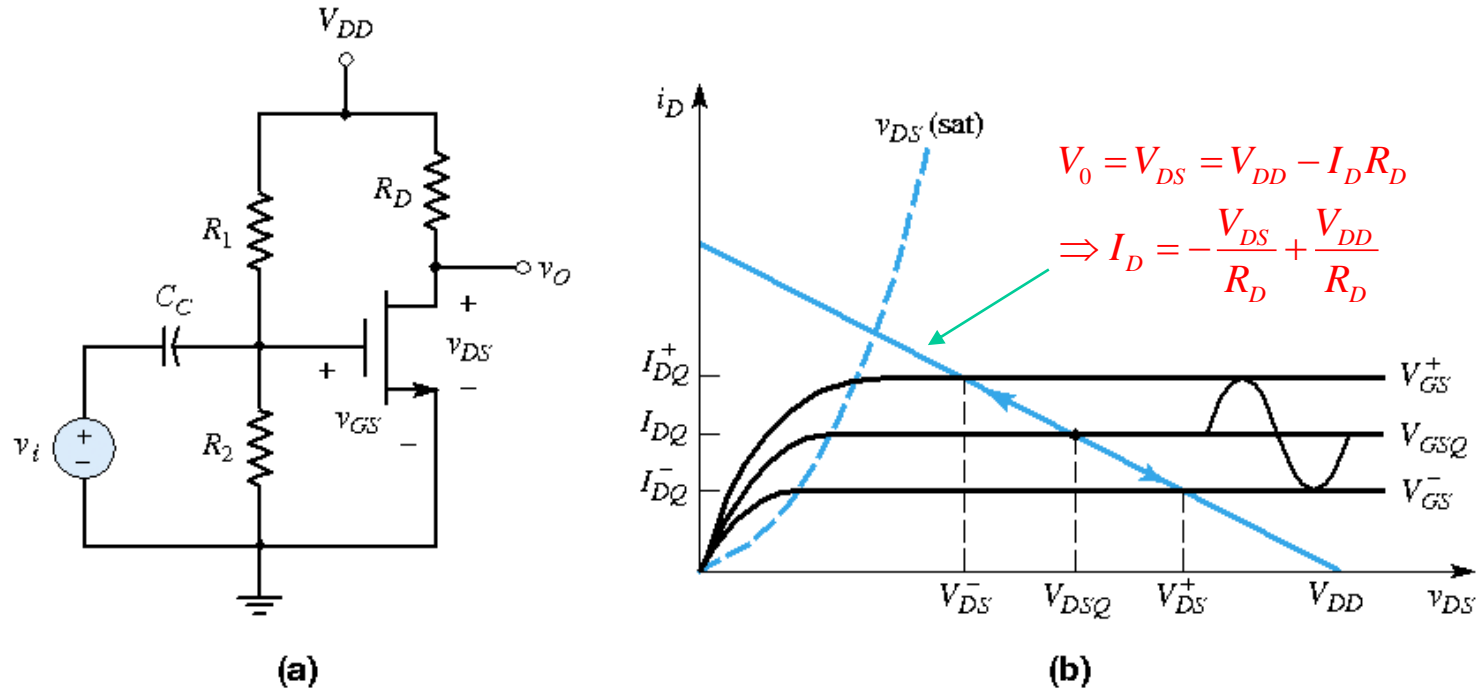


Figure 5.47 (a) An NMOS common-source circuit with a time-varying signal coupled to the gate and (b) transistor characteristics, load line, and superimposed sinusoidal signals

Constant-Current Biasing

EXAMPLE 3.17

Objective: Analyze the circuit shown in Figure 3.53(a). Determine the bias current I_{Q1} , the gate-to-source voltages of the transistors, and the drain-to-source voltage of M_1 .

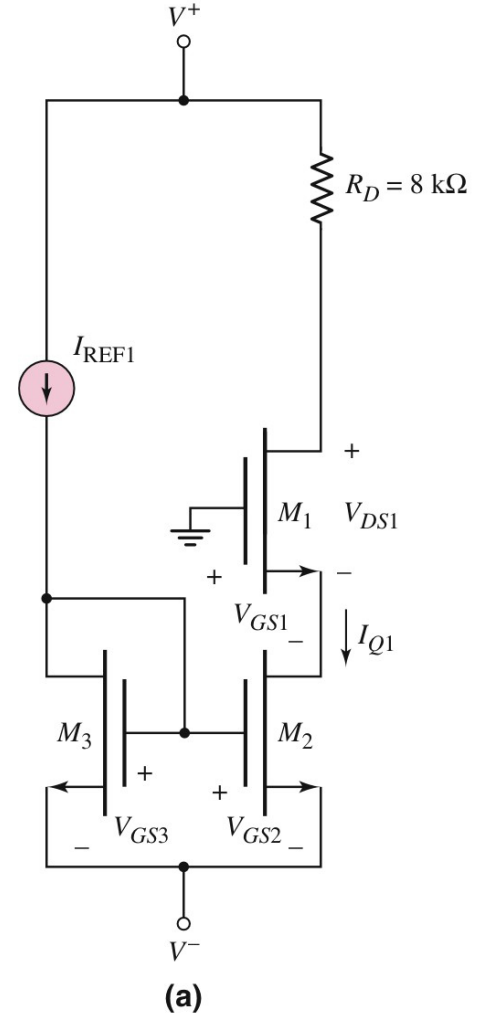
Assume circuit parameters of $I_{REF1} = 200 \mu\text{A}$, $V^+ = 2.5 \text{ V}$, and $V^- = -2.5 \text{ V}$. Assume transistor parameters of $V_{TN} = 0.4 \text{ V}$ (all transistors), $\lambda = 0$ (all transistors), $K_{n1} = 0.25 \text{ mA/V}^2$, and $K_{n2} = K_{n3} = 0.15 \text{ mA/V}^2$.

Solution:

實際上，於飽和狀態下的電流公式：

$$I_D = K_n \left[(V_{GS} - V_{TN})^2 (1 + \lambda V_{DS}) \right]$$

但 λ 值通常很小，可忽略。



Comment: Since the current mirror transistors M_2 and M_3 are matched (identical parameters) and since the gate-to-source voltages are the same in the two transistors, the bias current, I_{Q1} , is equal to (i.e., mirrors) the reference current, I_{REF1} .

Constant-Current Biasing

EXAMPLE 3.17

Objective: Analyze the circuit shown in Figure 3.53(a). Determine the bias current I_{Q1} , the gate-to-source voltages of the transistors, and the drain-to-source voltage of M_1 .

Assume circuit parameters of $I_{REF1} = 200 \mu\text{A}$, $V^+ = 2.5 \text{ V}$, and $V^- = -2.5 \text{ V}$. Assume transistor parameters of $V_{TN} = 0.4 \text{ V}$ (all transistors), $\lambda = 0$ (all transistors), $K_{n1} = 0.25 \text{ mA/V}^2$, and $K_{n2} = K_{n3} = 0.15 \text{ mA/V}^2$.

Solution:

(a) $I_{D3} = I_{REF1} = 200 \mu\text{A}$

(b) M_3 **must be** biased in the saturation region.

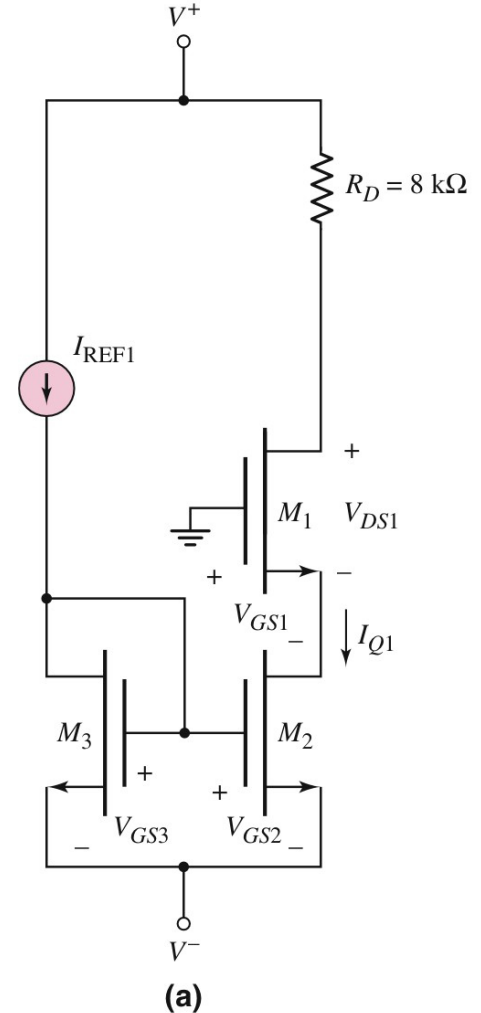
$$I_{D3} = K_{n3} (V_{GS3} - V_{TN})^2$$

$$\Rightarrow V_{GS3} = \sqrt{\frac{I_{D3}}{K_{n3}}} + V_{TN} = \sqrt{\frac{0.2}{0.15}} + 0.4 = 1.555 \text{ V}$$

(c) $V_{GS3} = V_{GS2} = 1.555 \text{ V}$

Assume M_2 is biased in the saturation region

$$I_{D2} = I_{Q1} = K_{n2} (V_{GS2} - V_{TN})^2 = 0.15 (1.555 - 0.4)^2 = 200 \mu\text{A}$$



(d) Assume M_1 is biased in the saturation region

$$I_{D1} = I_{Q1} = K_{n1} (V_{GS1} - V_{TN})^2$$
$$\Rightarrow V_{GS1} = \sqrt{\frac{I_{Q1}}{K_{n1}}} + V_{TN} = \sqrt{\frac{0.2}{0.25}} + 0.4 = 1.29 \text{ V}$$

(e) $V_{DS1} = V^+ - I_{Q1}R_D - V_{S1}$

$$= V^+ - I_{Q1}R_D - (-V_{GS1})$$
$$= 2.5 - (0.2)(8) - (-1.29) = 2.19 \text{ V}$$

(f) Check: $V_{DS1} = 2.19 \text{ V} > V_{DS1,\text{sat}} = V_{GS1} - V_{TN} = 1.29 - 0.4 = 0.89 \text{ V}$

The transistor M_1 is indeed biased in the saturation region

$$V_{DS2} = V_{D2} - V_{S2} = V_{S1} - V^- = -1.29 - (-2.5) = 1.21 \text{ V}$$

$$V_{DS2} > V_{DS2,\text{sat}} = V_{GS2} - V_{TN} = 1.555 - 0.4 = 1.155 \text{ V}$$

The transistor M_2 is indeed biased in the saturation region

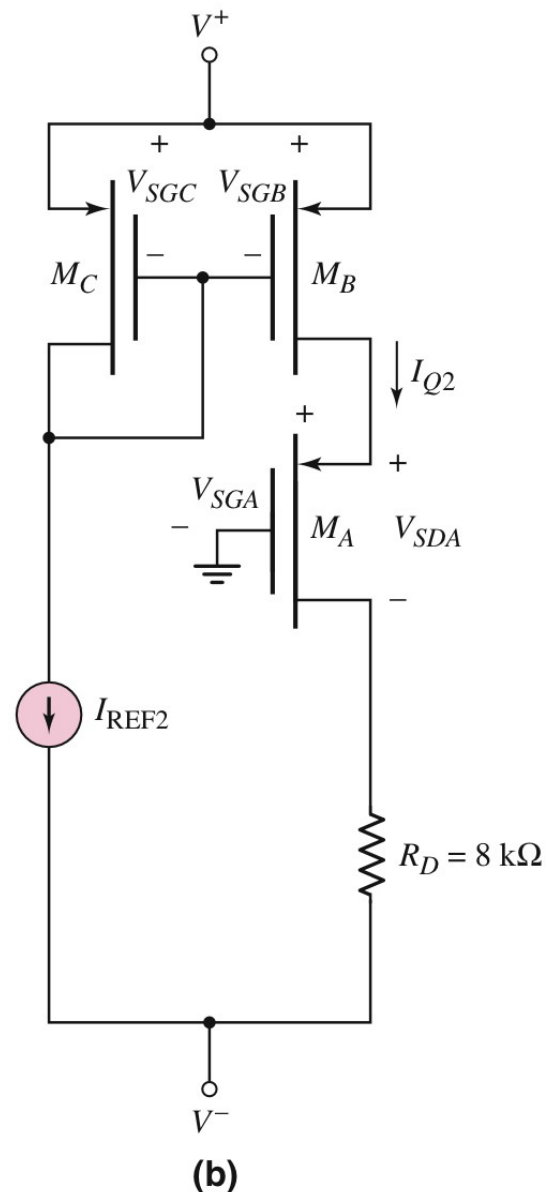
Comment: Since the current mirror transistors M_2 and M_3 are matched (identical parameters) and since the gate-to-source voltages are the same in the two transistors, the bias current, I_{Q1} , is equal to (i.e., mirrors) the reference current, I_{REF1} .

EXAMPLE 3.18

Objective: Design the circuit shown in Figure 3.53(b) to provide a bias current of $I_{Q2} = 150 \mu\text{A}$.

Assume circuit parameters of $I_{\text{REF2}} = 250 \mu\text{A}$, $V^+ = 3 \text{ V}$, and $V^- = -3 \text{ V}$. Assume transistor parameters of $V_{TP} = -0.6 \text{ V}$ (all transistors), $\lambda = 0$ (all transistors), $k'_p = 40 \mu\text{A/V}^2$ (all transistors), $W/L_C = 15$, and $W/L_A = 25$.

Solution:



EXAMPLE 3.18

Objective: Design the circuit shown in Figure 3.53(b) to provide a bias current of $I_{Q2} = 150 \mu\text{A}$.

Assume circuit parameters of $I_{REF2} = 250 \mu\text{A}$, $V^+ = 3 \text{ V}$, and $V^- = -3 \text{ V}$. Assume transistor parameters of $V_{TP} = -0.6 \text{ V}$ (all transistors), $\lambda = 0$ (all transistors), $k'_p = 40 \mu\text{A/V}^2$ (all transistors), $W/L_C = 15$, and $W/L_A = 25$.

Solution:

- (1) $I_{Q2} \neq I_{REF2} \Rightarrow \left(\frac{W}{L}\right)_B \neq \left(\frac{W}{L}\right)_C$
- (2) M_C **must be** biased in the saturation region.

$$I_{DC} = I_{REF2} = \frac{k'_n}{2} \cdot \left(\frac{W}{L}\right)_C (V_{SGC} + V_{TP})^2$$

$$\Rightarrow 250 = \frac{40}{2} (15) [V_{SGC} + (-0.6)]^2$$

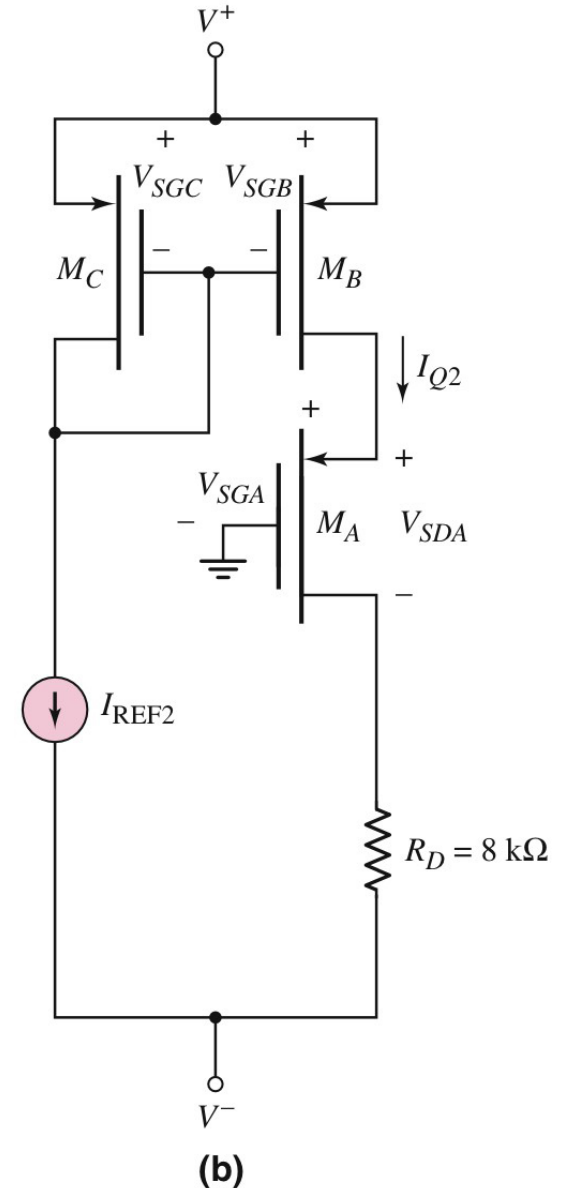
$$\Rightarrow V_{SGC} = \sqrt{\frac{250}{300}} + 0.6 = 1.513 \text{ V}$$

$$(3) V_{SGB} = V_{SGC} = 1.513 \text{ V}$$

- (4) Assume that M_B is biased in the saturation region

$$I_B = I_{Q2} = \frac{k'_n}{2} \cdot \left(\frac{W}{L}\right)_B (V_{SGB} + V_{TP})^2$$

$$\Rightarrow 150 = \frac{40}{2} \cdot \left(\frac{W}{L}\right)_B [1.513 + (-0.6)]^2 \Rightarrow \left(\frac{W}{L}\right)_B = 9$$



(5) Assume that M_A is biased in the saturation region

$$I_{DA} = I_{Q2} = \frac{k'_n}{2} \cdot \left(\frac{W}{L} \right)_A (V_{SGA} + V_{TP})^2$$

$$\Rightarrow 150 = \frac{40}{2} (25) (V_{SGA} + (-0.6))^2$$

$$\Rightarrow V_{SGA} = 1.148 \text{ V}$$

(6) $V_{SGA} = V_{SA} - V_{GA} = V_{SA} = 1.148 \text{ V}$

$$V_{SDA} = V_{SA} - I_{Q2} R_D - V^- = 1.148 - (-0.15)(8) - (-3) = 2.95 \text{ V}$$

(7) Check: $V_{SDA} = 2.95 \text{ V} > V_{SDA,\text{sat}} = V_{SGA} + V_{TP} = 1.148 + (-0.6) = 0.548 \text{ V}$

The transistor M_A is indeed biased the saturation region

$$V_{SDB} = V_{SB} - V_{DB} = V^+ - V_S = 3 - 1.148 = 1.852 \text{ V}$$

$$V_{SDB} > V_{SDB,\text{sat}} = V_{SGB} + V_{TP} = 1.513 + (-0.6) = 0.913 \text{ V}$$

The transistor M_B is indeed biased the saturation region

Constant-Current Biasing

(1) M_3 and M_4 are biased in the saturation region

$$(2) K_{n3}(V_{GS3} - V_{TN3})^2 = K_{n4}(V_{GS4} - V_{TN4})^2$$

$$(3) V_{GS4} + V_{GS3} = -V^-$$

$$(4) V_{GS3} = \frac{-V^- - V_{TN4} + V_{TN3}\sqrt{K_{n3}/K_{n4}}}{1 + \sqrt{K_{n3}/K_{n4}}}$$

$$(5) I_Q = K_{n2}(V_{GS3} - V_{TN2})^2$$

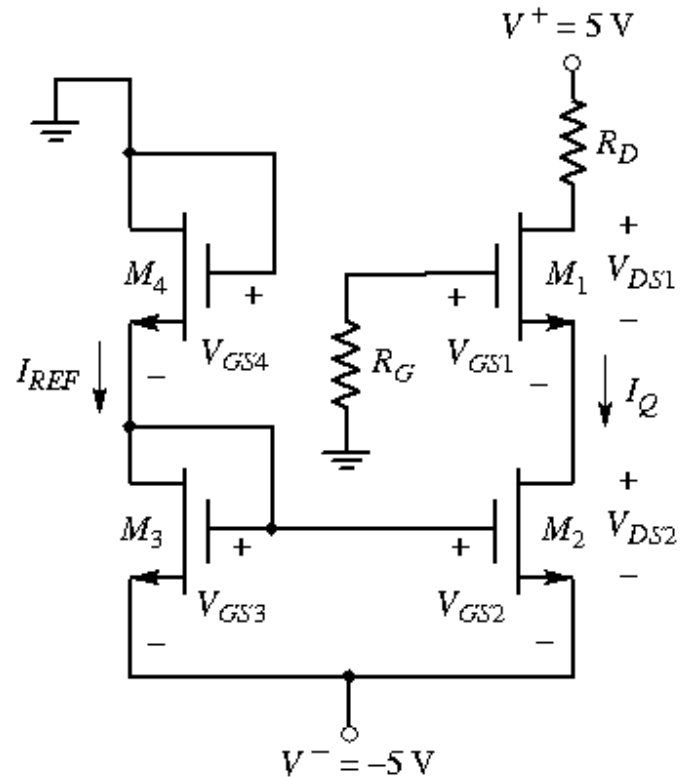


Figure 5.43 Implementation of a MOSFET constant-current source

Example 5.13 Objective: Determine the currents and voltages in a MOSFET constant-current source.

For the circuit shown in Figure 5.43, the transistor parameters are: $K_{n1} = 0.2 \text{ mA/V}^2$, $K_{n2} = K_{n3} = K_{n4} = 0.1 \text{ mA/V}^2$, and $V_{TN1} = V_{TN2} = V_{TN3} = V_{TN4} = 1 \text{ V}$.

Solution:

$$(1) V_{GS3} = \frac{\sqrt{\frac{0.1}{0.1}}[5-1]+1}{1+\sqrt{\frac{0.1}{0.1}}} = 2.5 \text{ V}$$

$$(2) I_Q = (0.1) \cdot (2.5-1)^2 = 0.225 \text{ mA}$$

$$(3) I_Q = K_{n1} (V_{GS1} - V_{TN1})^2$$

$$\Rightarrow 0.225 = (0.2)(V_{GS1} - 1)^2$$

$$\Rightarrow V_{GS1} = 2.06 \text{ V}$$

$$(4) V_{GS1} = V_{G1} - V_{S1} = 0 - V_{S1} = 2.06 \text{ V} \Rightarrow V_{S1} = -2.06 \text{ V}$$

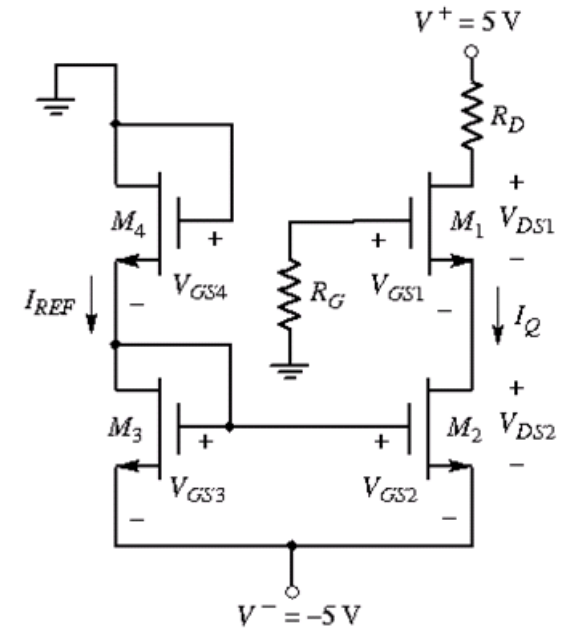
$$(5) V^- + V_{DS2} = V_{S1}$$

$$\Rightarrow V_{DS2} = V_{S1} - V^- = -2.06 - (-5) = 2.94 \text{ V}$$

$$(6) \text{ Check: } V_{DS2} = V_{D2} - V_{S2} = V_{S1} - V^- = -2.06 - (-5) = 2.94 \text{ V}$$

$$V_{DS2} > V_{DS2,\text{sat}} = V_{GS2} - V_{TN2} = 2.5 - 1 = 1.5 \text{ V}$$

The transistor M_2 is indeed based the saturation region

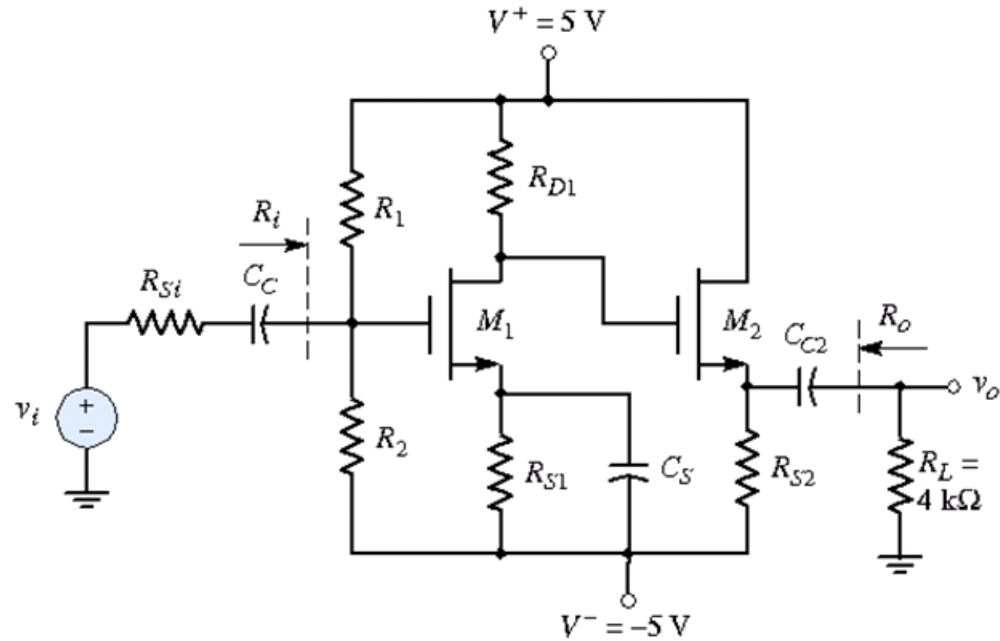


Multitransistor Circuit: Cascade Configuration

Design Example 6.14 Objective: Design the biasing of a multistage MOSFET circuit to meet specific requirements.

Consider the circuit shown in Figure 6.49 with transistor parameters $K_{n1} = 500 \mu\text{A}/\text{V}^2$, $K_{n2} = 200 \mu\text{A}/\text{V}^2$, $V_{TN1} = V_{TN2} = 1.2 \text{ V}$, and $\lambda_1 = \lambda_2 = 0$. Design the circuit such that $I_{DQ1} = 0.2 \text{ mA}$, $I_{DQ2} = 0.5 \text{ mA}$, $V_{DSQ1} = V_{DSQ2} = 6 \text{ V}$, and $R_i = 100 \text{ k}\Omega$. Let $R_{Si} = 4 \text{ k}\Omega$.

Solution:



Multitransistor Circuit: Cascade Configuration

Design Example 6.14 Objective: Design the biasing of a multistage MOSFET circuit to meet specific requirements.

Consider the circuit shown in Figure 6.49 with transistor parameters $K_{n1} = 500 \mu\text{A}/\text{V}^2$, $K_{n2} = 200 \mu\text{A}/\text{V}^2$, $V_{TN1} = V_{TN2} = 1.2 \text{ V}$, and $\lambda_1 = \lambda_2 = 0$. Design the circuit such that $I_{DQ1} = 0.2 \text{ mA}$, $I_{DQ2} = 0.5 \text{ mA}$, $V_{DSQ1} = V_{DSQ2} = 6 \text{ V}$, and $R_i = 100 \text{ k}\Omega$. Let $R_{Si} = 4 \text{ k}\Omega$.

Solution:

$$(1) V^- + I_{DQ2}R_{S2} + V_{DS2} = V^+$$

$$\Rightarrow V_{DSQ2} = V^+ - V^- - I_{DQ2}R_{S2}$$

$$\Rightarrow 6 = 5 - (-5) - (0.5)R_{S2} \Rightarrow R_{S2} = 8 \text{ k}\Omega$$

(2) Assume that M_2 is biased in the saturation region

$$I_{DQ2} = K_{n2}(V_{GS2} - V_{TN2})^2$$

$$\Rightarrow 0.5 = 0.2(V_{GS2} - 1.2)^2$$

$$\Rightarrow V_{GS2} = 2.78 \text{ V}$$

(3) Check: $V_{DS2} = 6 \text{ V} > V_{DS2,\text{sat}} = V_{GS2} - V_{TN2} = 2.78 - 1.2 = 1.58 \text{ V}$

The transistor M_2 is indeed biased in the saturation region

$$(4) V^+ - V_{DS2} = V_{S2} \Rightarrow 5 - 6 = V_{S2} = -1 \text{ V}$$

$$(5) V_{GS2} = V_{G2} - V_{S2}$$

$$\Rightarrow 2.78 = V_{G2} - (-1)$$

$$\Rightarrow V_{G2} = 1.78 \text{ V}$$

$$(6) V_{G2} = V_{D1} = 1.78 \text{ V}$$

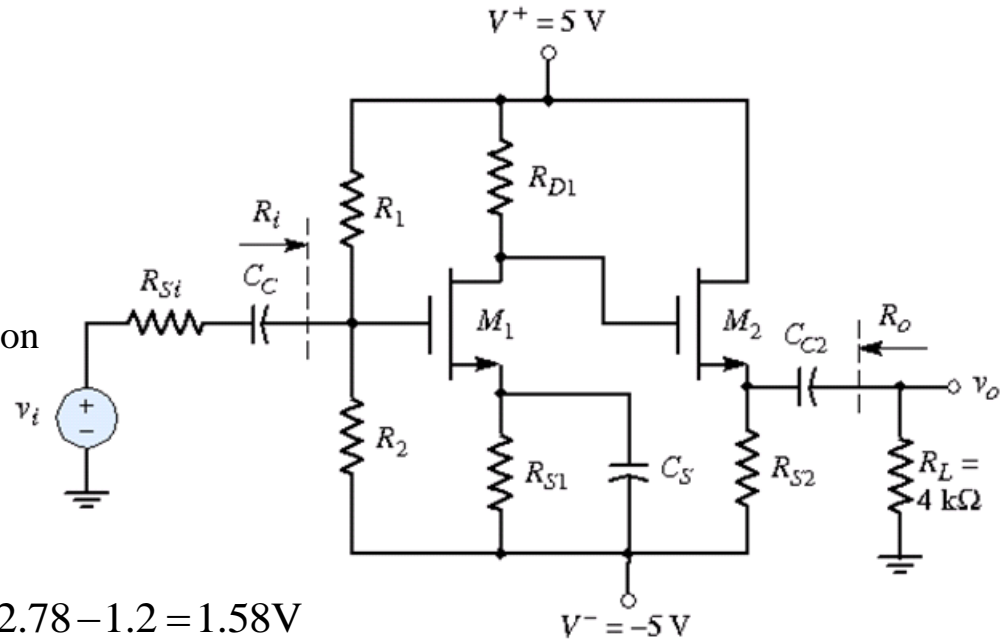
$$V^+ = V_{D1} + I_{DQ1}R_{D1}$$

$$\Rightarrow 5 = 1.78 + (0.2)R_{D1}$$

$$\Rightarrow R_{D1} = 16.1 \text{ k}\Omega$$

$$(7) V_{DSQ1} = V_{D1} - V_{S1}$$

$$\Rightarrow V_{S1} = V_{D1} - V_{DSQ1} = 1.78 - 6 = -4.22 \text{ V}$$



$$(8) V_{S1} = V^- + I_{D1} R_{S1}$$

$$\Rightarrow -4.22 = -5 + (0.2) R_{S1} \Rightarrow R_{S1} = 3.9 \text{ k}\Omega$$

(9) Assume that M_1 is biased in the saturation region

$$I_{DQ1} = K_{n1} (V_{GS1} - V_{TN1})^2$$

$$\Rightarrow 0.2 = 0.50 (V_{GS1} - 1.2)^2$$

$$\Rightarrow V_{GS1} = 1.83 \text{ V}$$

$$(10) \frac{R_2}{R_1 + R_2} = \frac{1}{R_1} \cdot \left(\frac{R_1 R_2}{R_1 + R_2} \right) = \frac{1}{R_1} \cdot R_i$$

$$V_{GS1} = \left(\frac{R_2}{R_1 + R_2} \right) (10) - I_{DQ1} R_{S1}$$

$$\frac{R_2}{R_1 + R_2} = \frac{1}{R_1} \cdot \left(\frac{R_1 R_2}{R_1 + R_2} \right) = \frac{1}{R_1} \cdot R_i$$

$$\Rightarrow 1.83 = \frac{1}{R_1} (100)(10) - (0.2)(3.9)$$

$$\Rightarrow R_1 = 383 \text{ k}\Omega$$

$$\Rightarrow R_2 = 135 \text{ k}\Omega$$

